

The Front-End of PANDA EMC and its Automatized Testing System (and Crystal Barrel exp.)

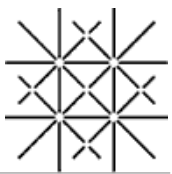
Irakli Keshelashvili, Fabian Mueller, Werner Erni, Michael Steinacher

Group of Prof. Bernd Krusche

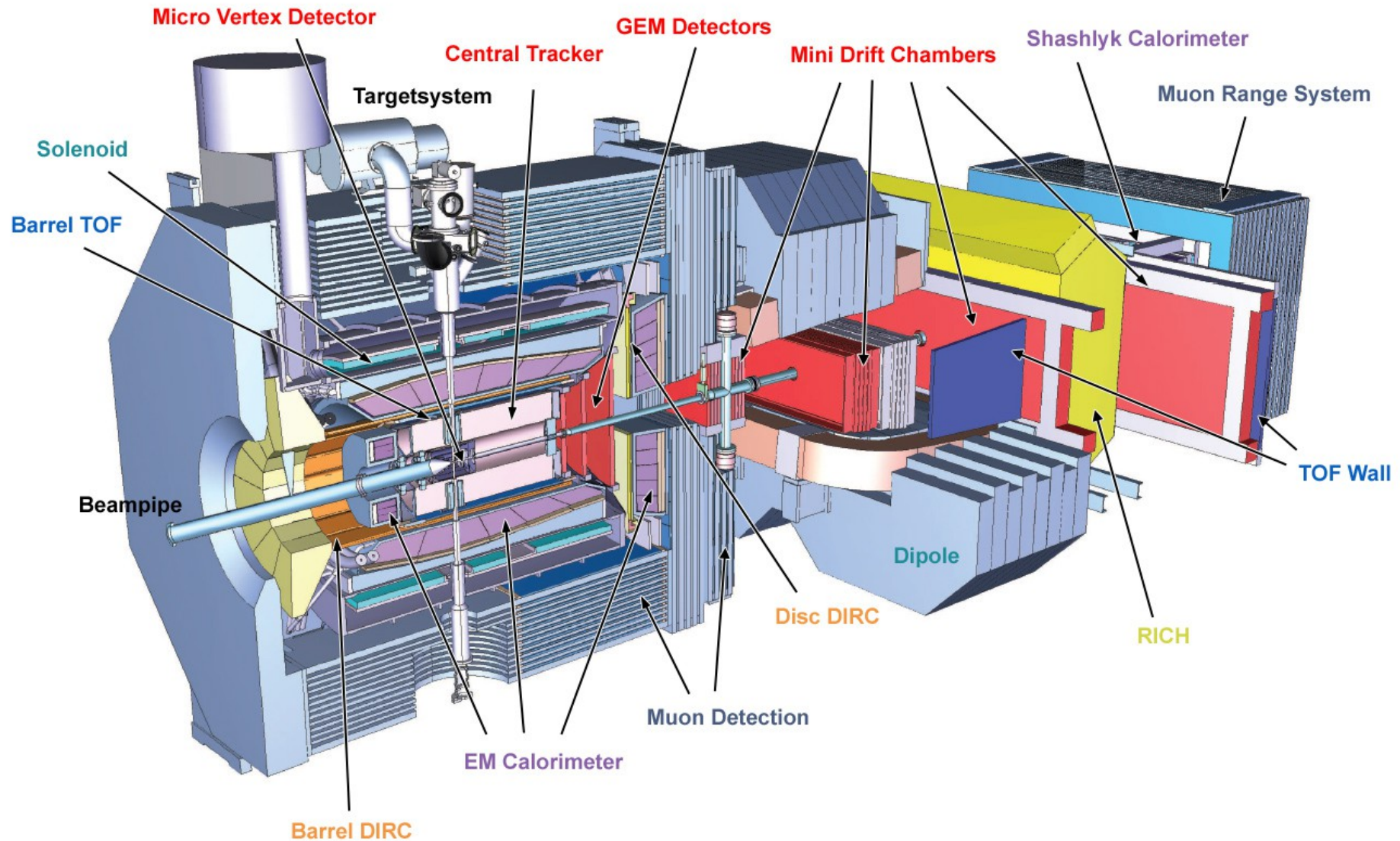
University of Basel

- Experiment PANDA / Crystal Barrel
- Basel Low Noise/Low Power (LNP) PreAmplifier
- Double Burst Laboratory Test
- Amplitude Linearity Laboratory Test
- Mass-production Test Setup
- Summary

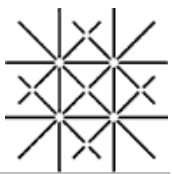
PANDA Detector



UNI
BASEL



PANDA Electromagnetic Calorimeter



UNI
BASEL

Material: PbWO_4 (-25C°)

Crystal size: 2 cm x 2 cm x 20 cm

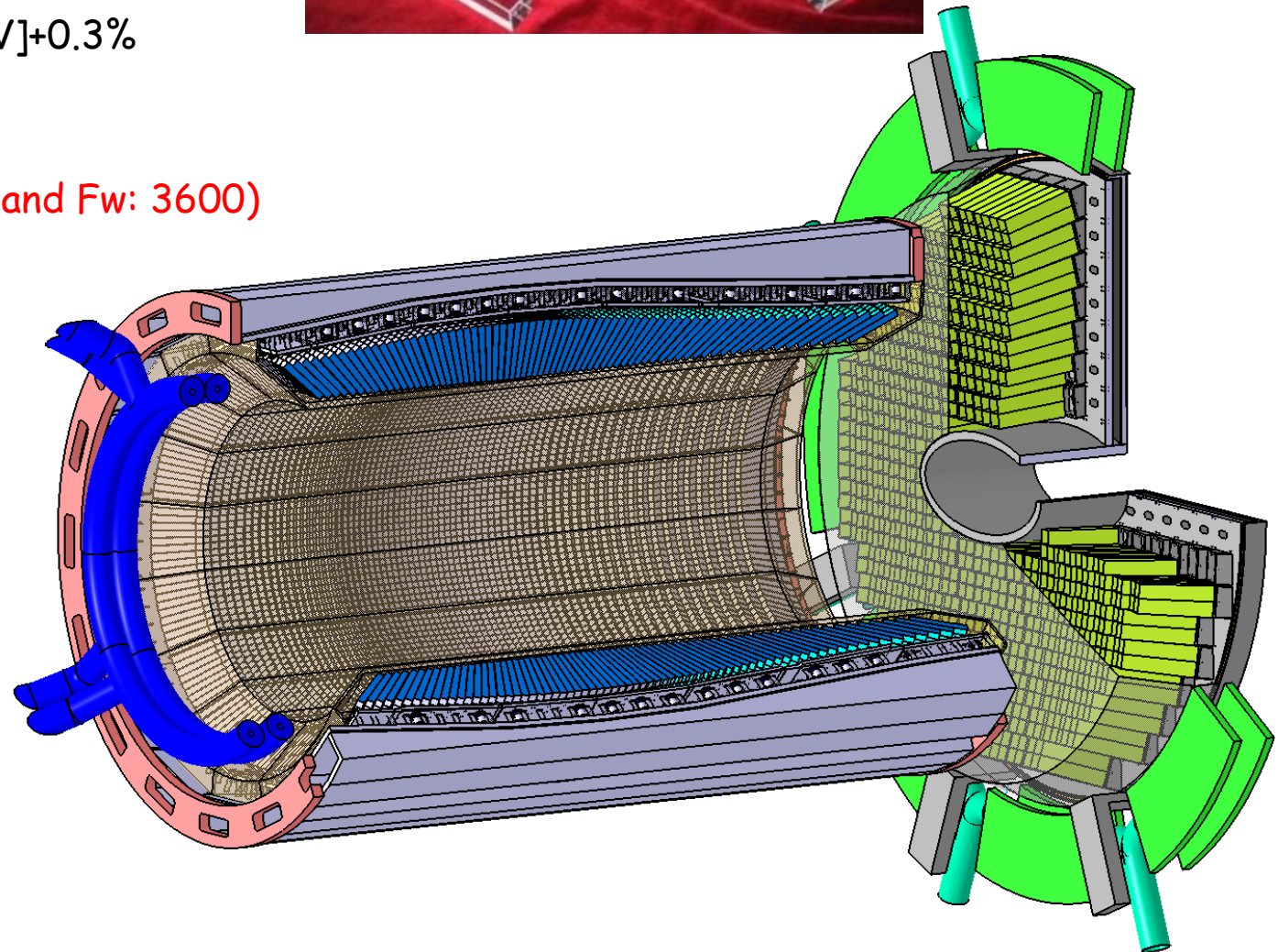
Thickness: $22 X_0$

Energy res.: $1.54\% / \sqrt{E/[GeV]} + 0.3\%$

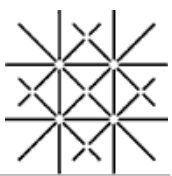
Time res.: $< 2 \text{ ns}$

of crystals: 15552 (Bk: 592 and Fw: 3600)

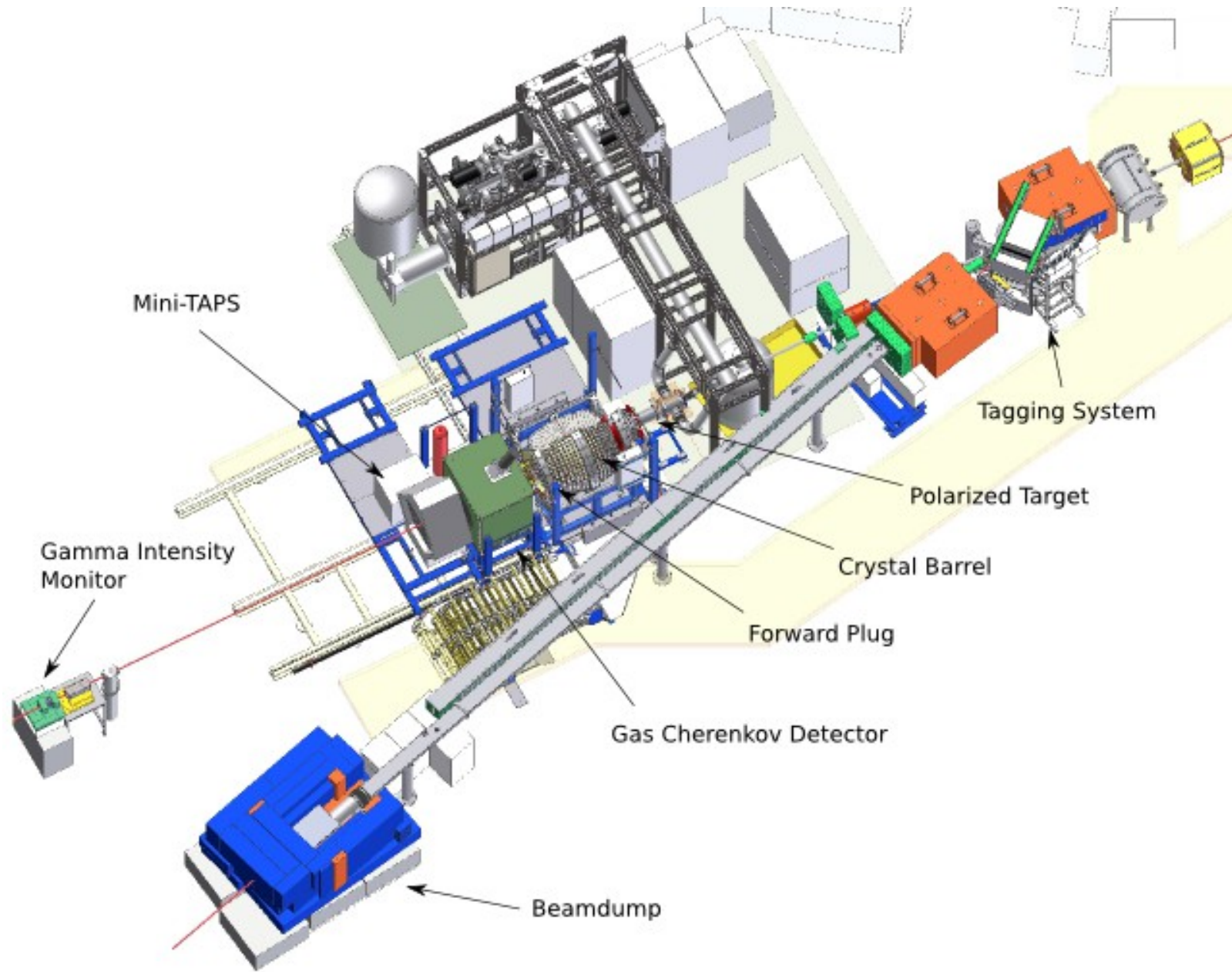
Coverage: $96\% 4\pi$



Crystal Barrel upgrade @ ELSA-Bonn



UNI
BASEL



Crystal Barrel upgrade @ ELSA-Bonn

Material: CsI(Tl)

Crystal size: $(6^\circ \times 6^\circ) \times 30$ cm

Thickness: $16.1 X_0$

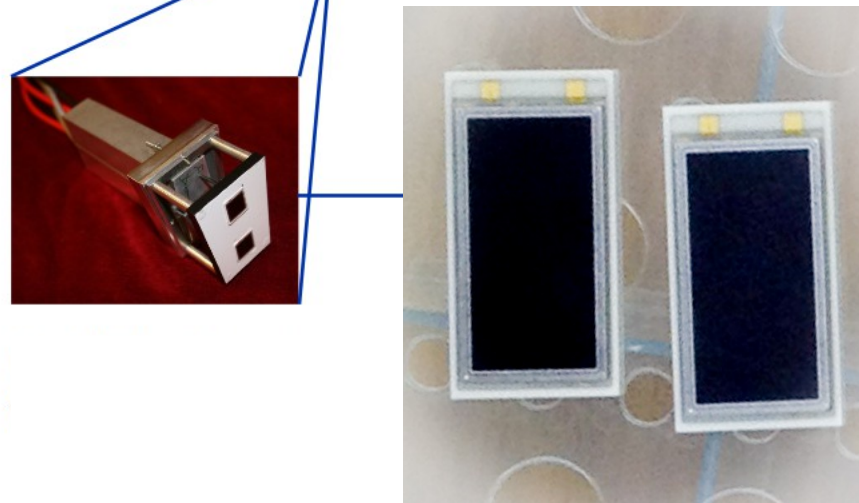
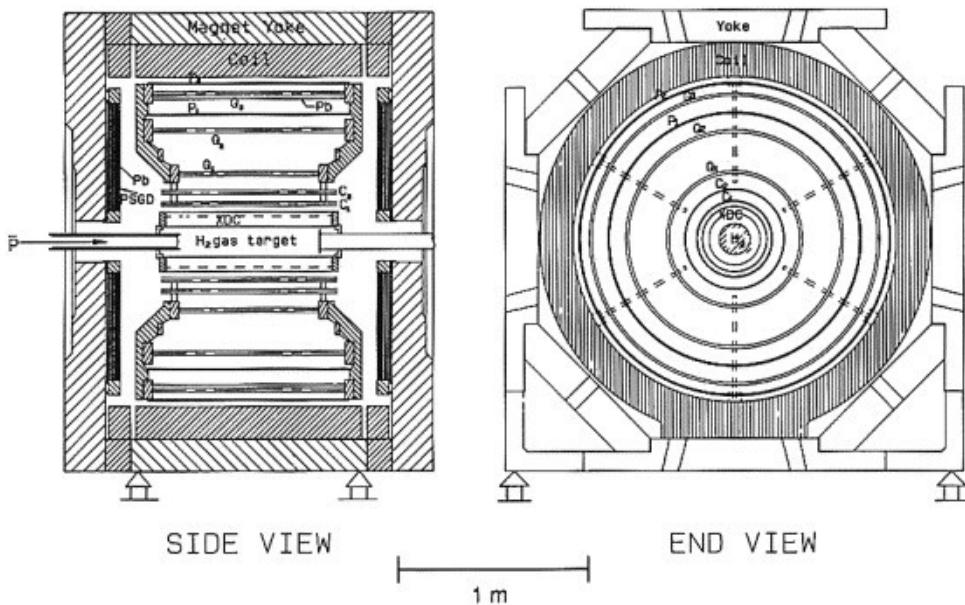
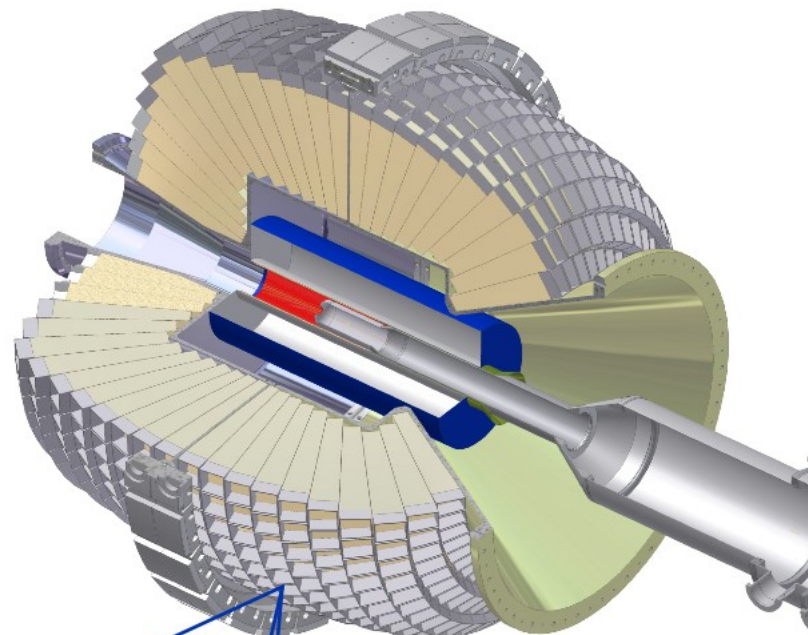
Energy res.: $1.3\% / \sqrt{E/[GeV]} + 2\%$

Time res.: **I level trigger - PIN no / APD YES!**

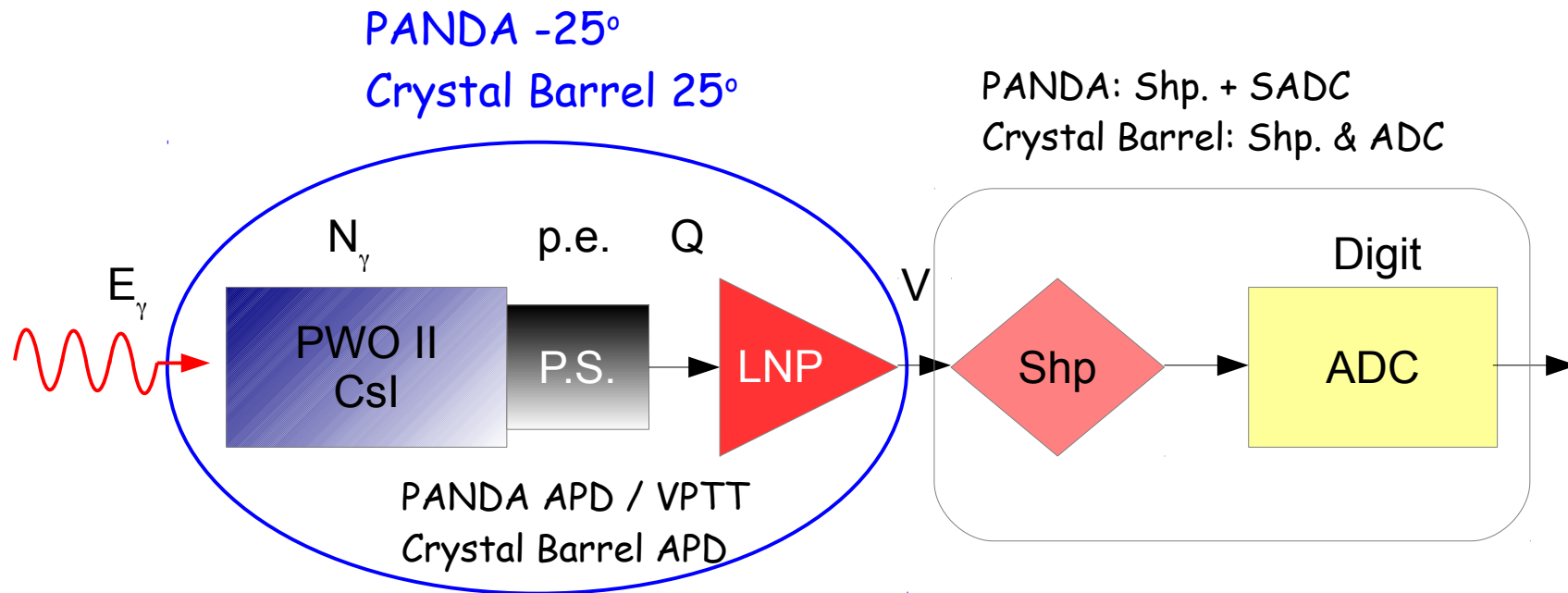
of crystals: 1380

Coverage: $98\% 4\pi$

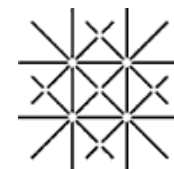
Now PIN --> future APD



General Concept of ReadOut

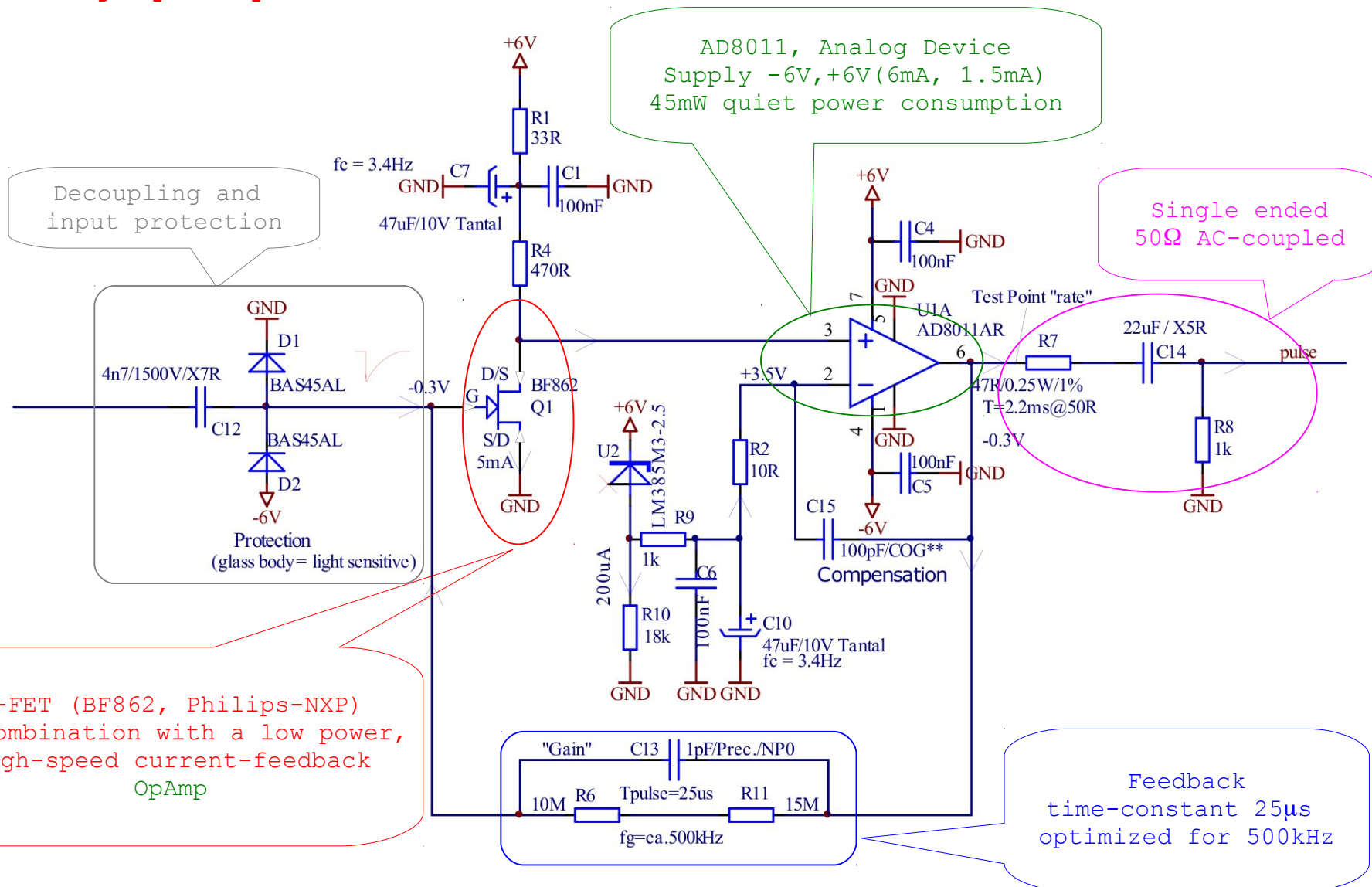


Basel LNP Preamplifier

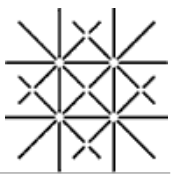


UNI
BASEL

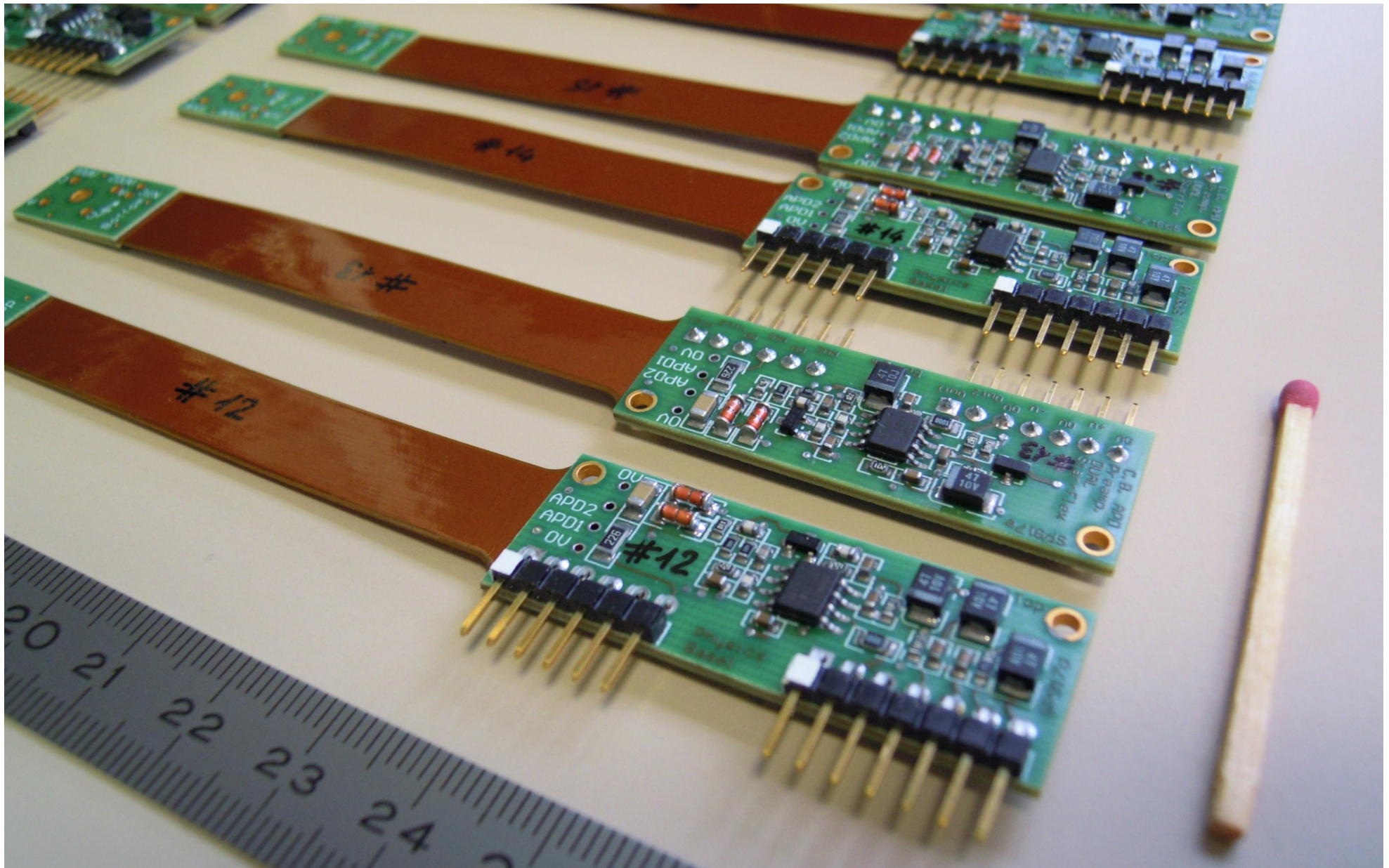
Low Noise / Low Power
discrete charge preamplifier

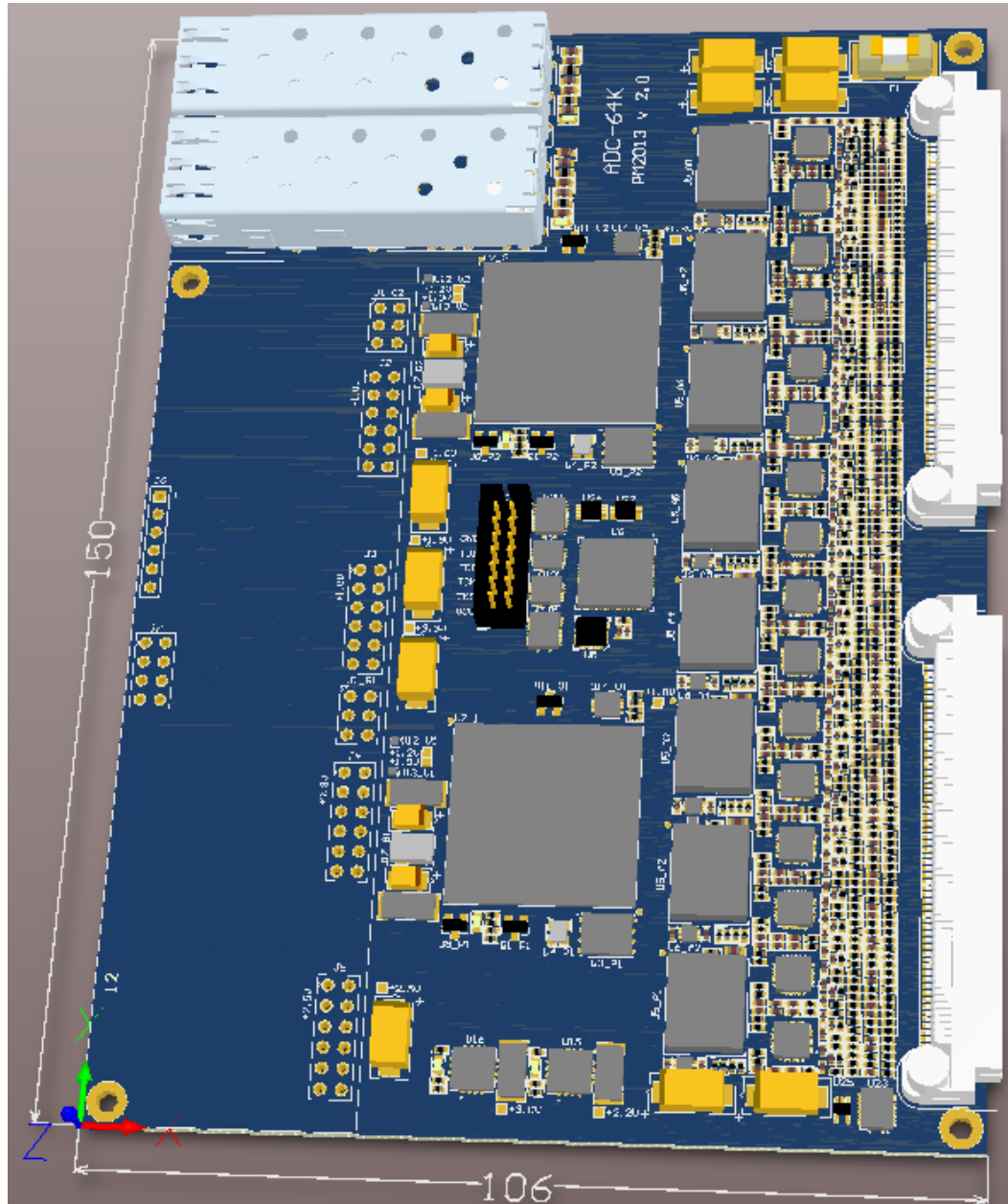


Dual LNP preamps for Crystal Barrel @ Bonn



UNI
BASEL





Design: Pawel Marciniewski
Uppsala Uni.

V1.1 - June 2013

- * Design clean-up
- * Block connectors -
Samtec ERF8-049-XX-X-D-RA
- * 64 - channels with individual gain,
no filter

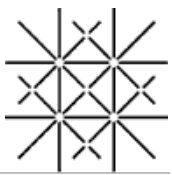
V1.2 - August 2013

- * Block connectors
- * Low power op-amp ADA4940-2
- * 32-ch. with gain $G = 0.5$, filtered
32-ch. with gain $G = 5.0$, filtered

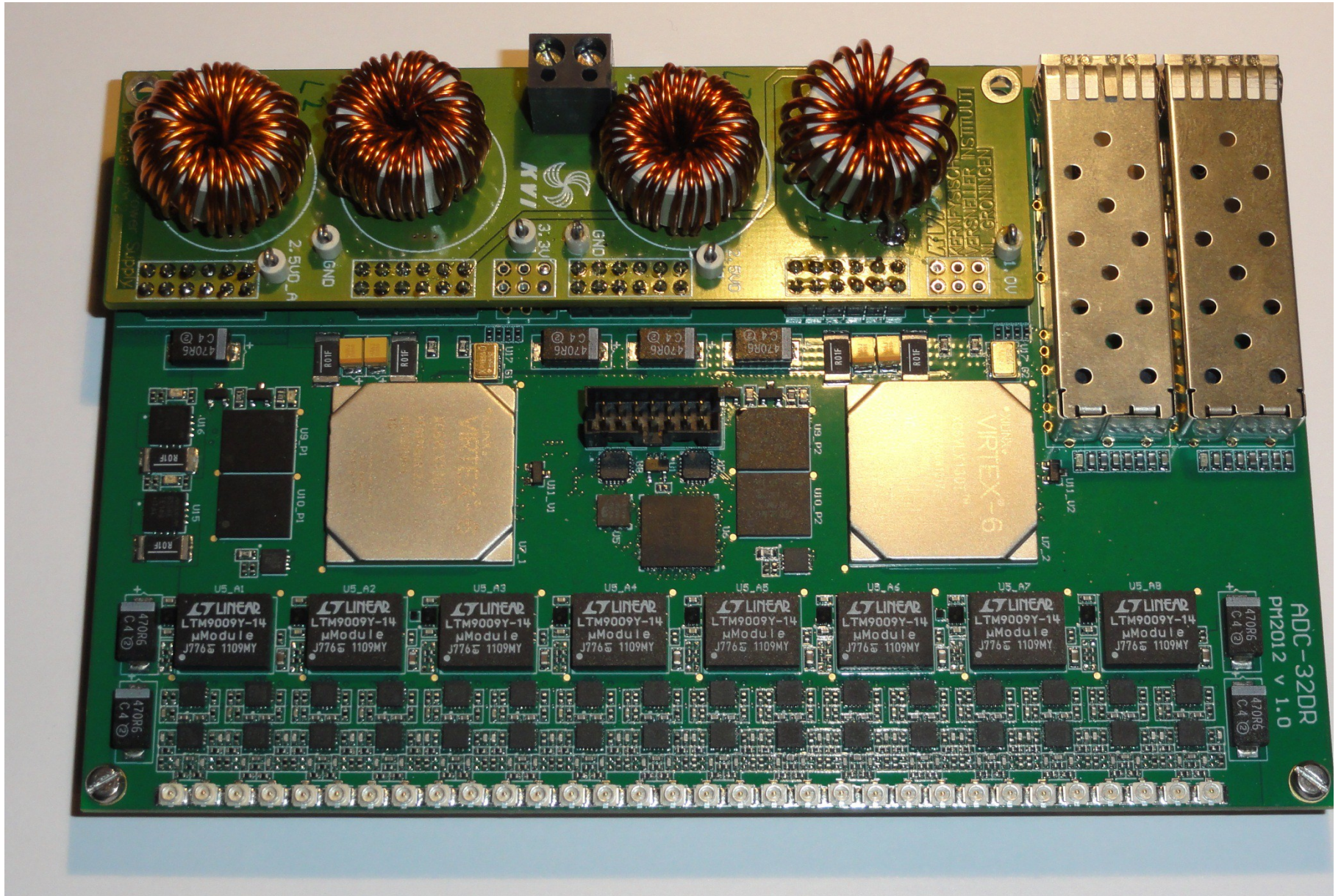
V2.0 - October 2013

- * Kintex-7

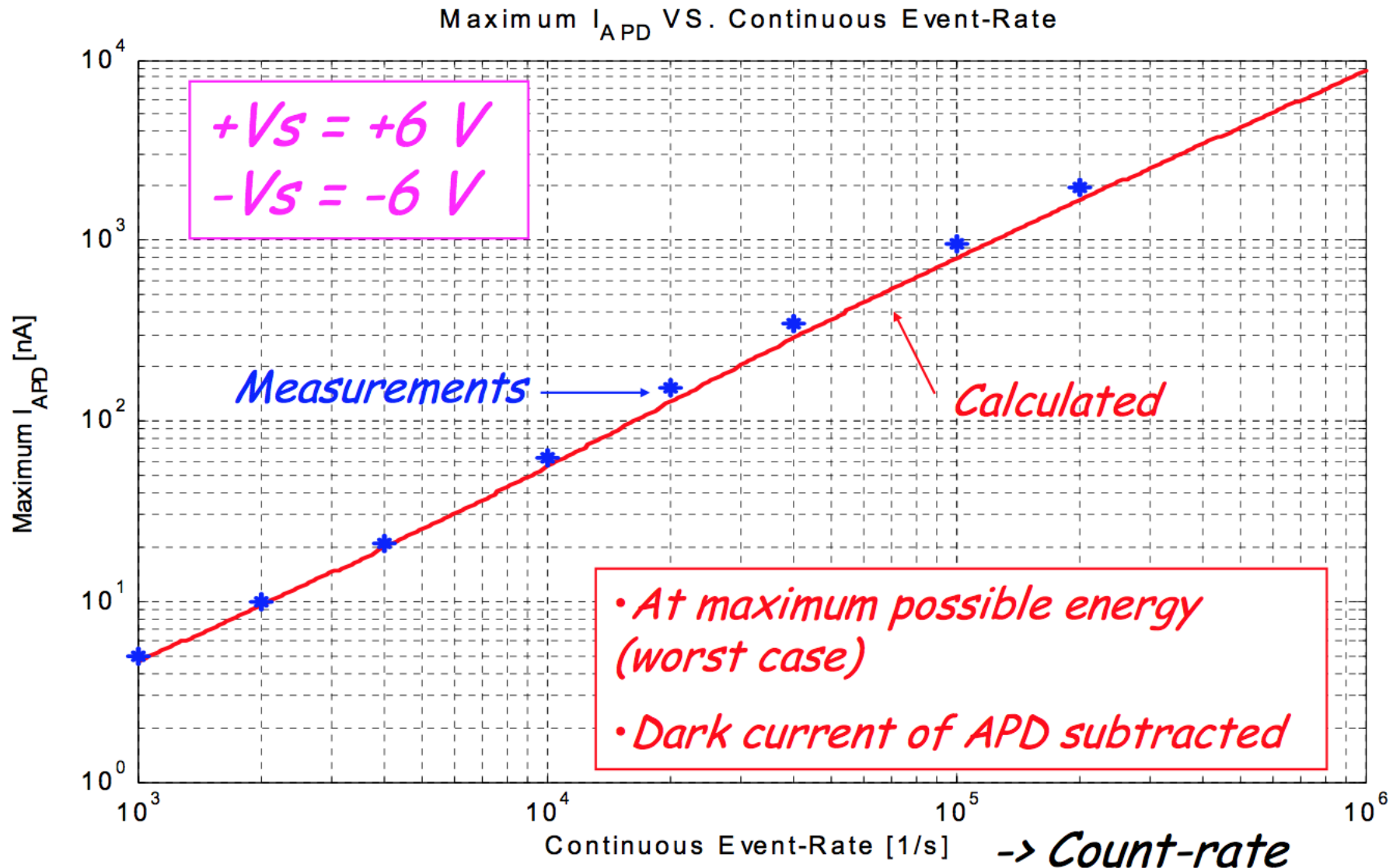
PANDA Shaper + SADC



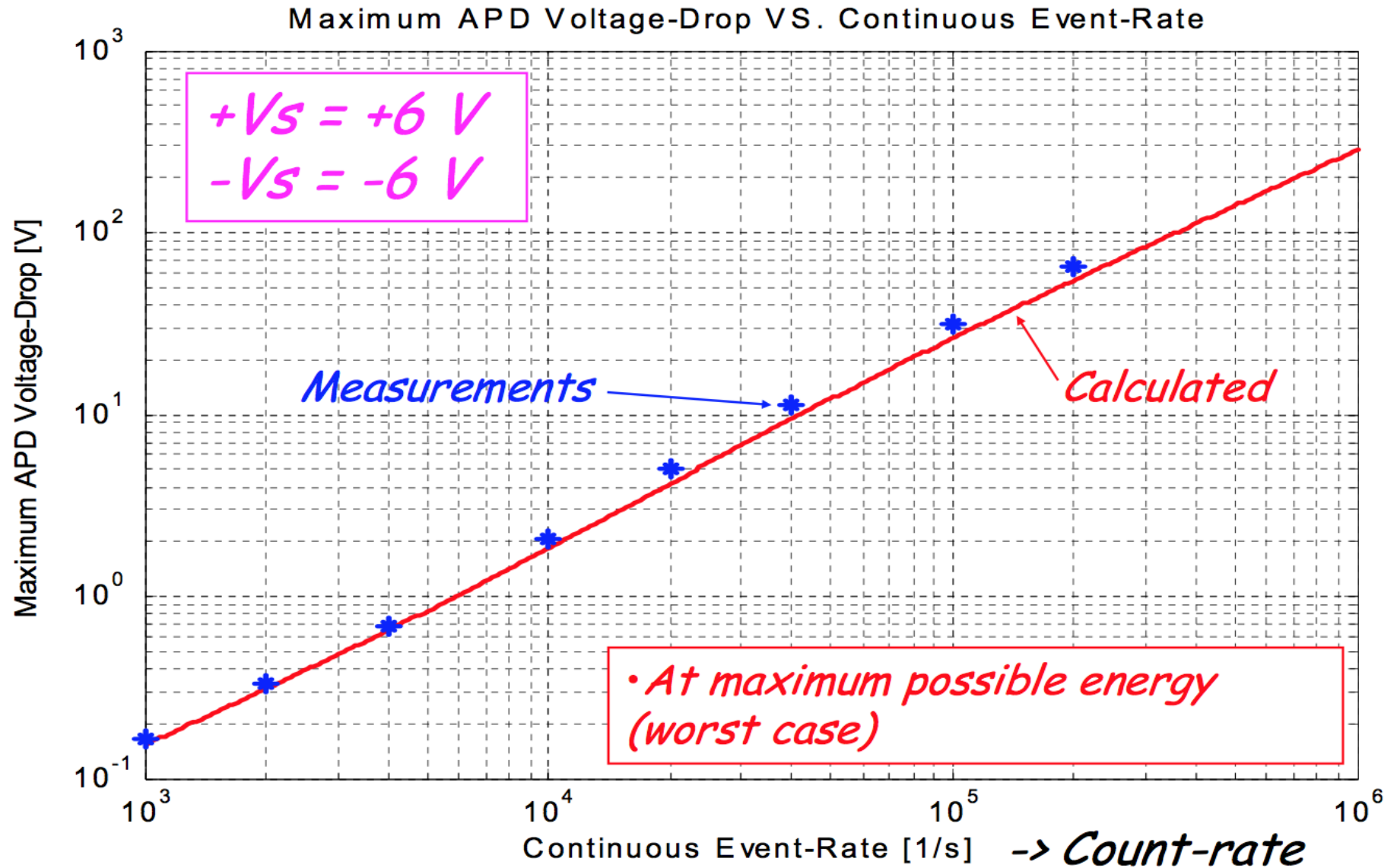
UNI
BASEL

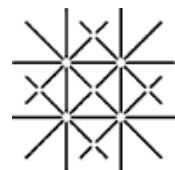


APD Current Vs Count-Rate



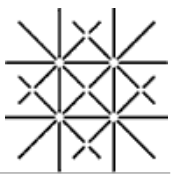
APD Voltage Vs Count-Rate



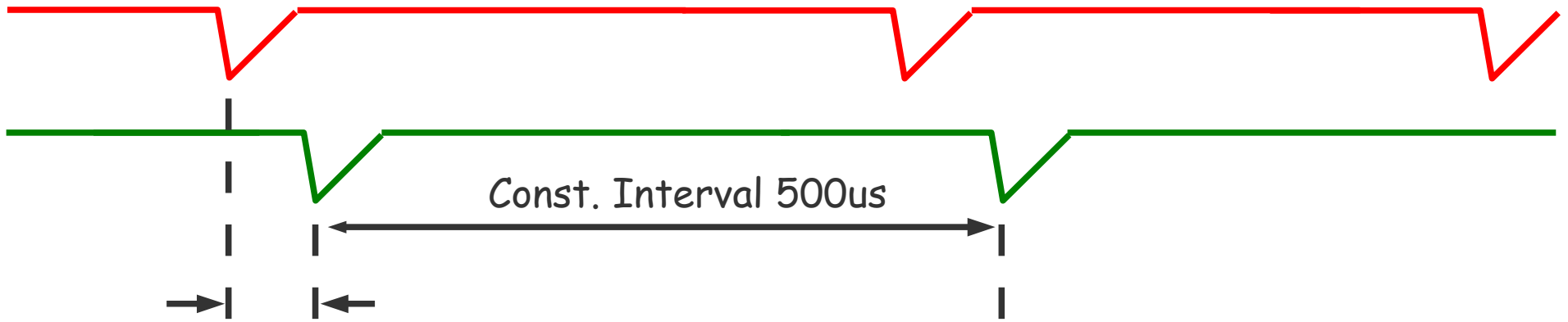
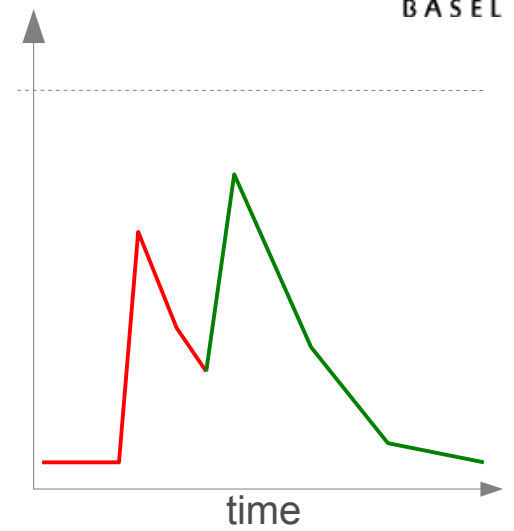
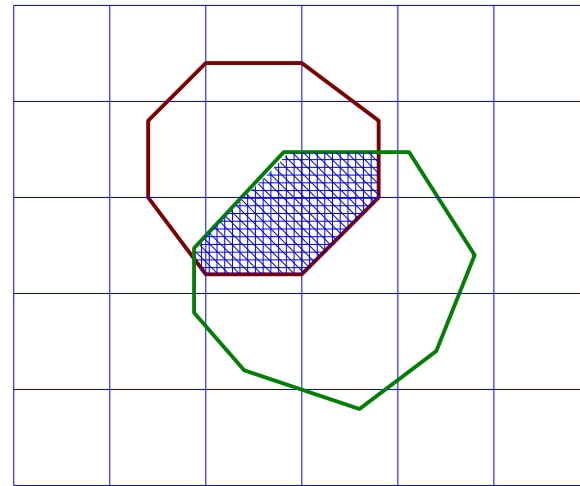
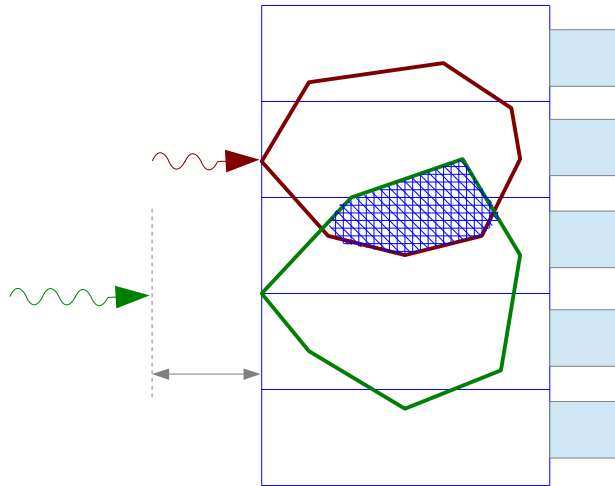


'Double Burst' Test Or Pileup Test

Double Burst Linearity



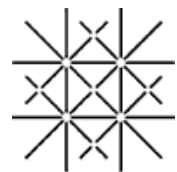
UNI
BASEL



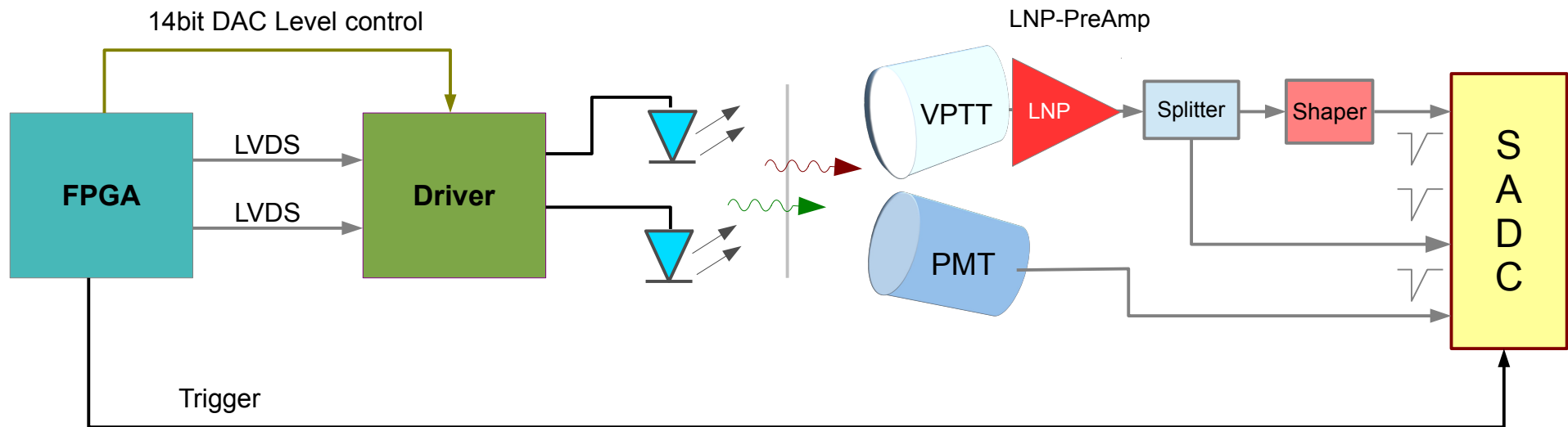
1us - 10us

1MHz - 100kHz

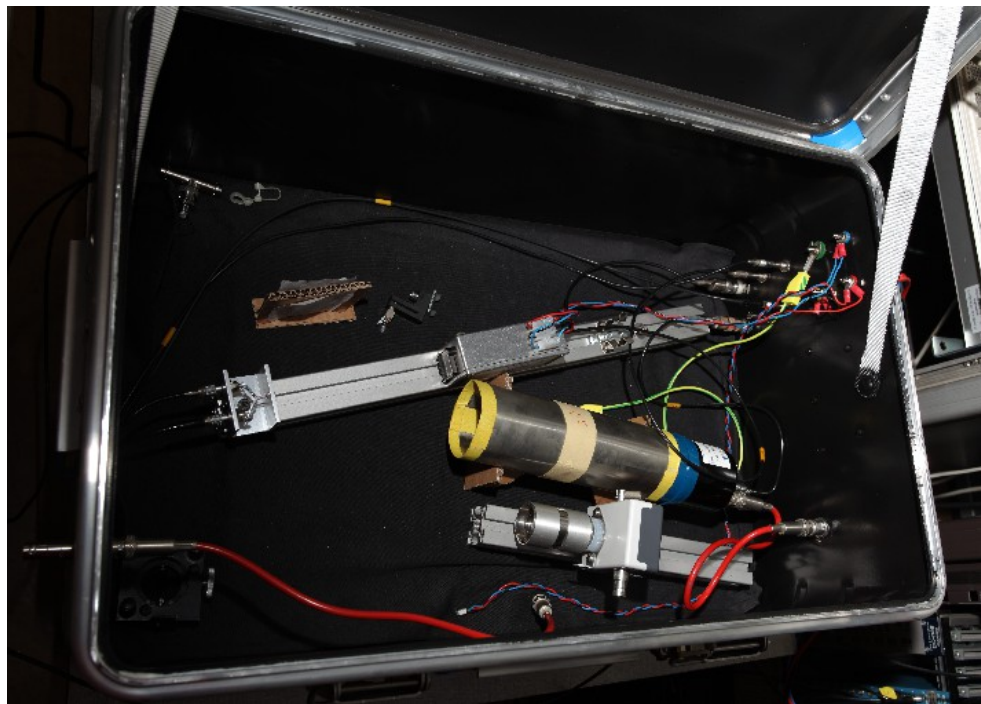
Double Burst Linearity - Measurement Method



UNI
BASEL



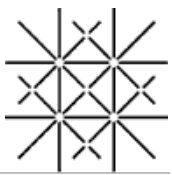
Xilinx Spartan-3AN
LED driver/signal



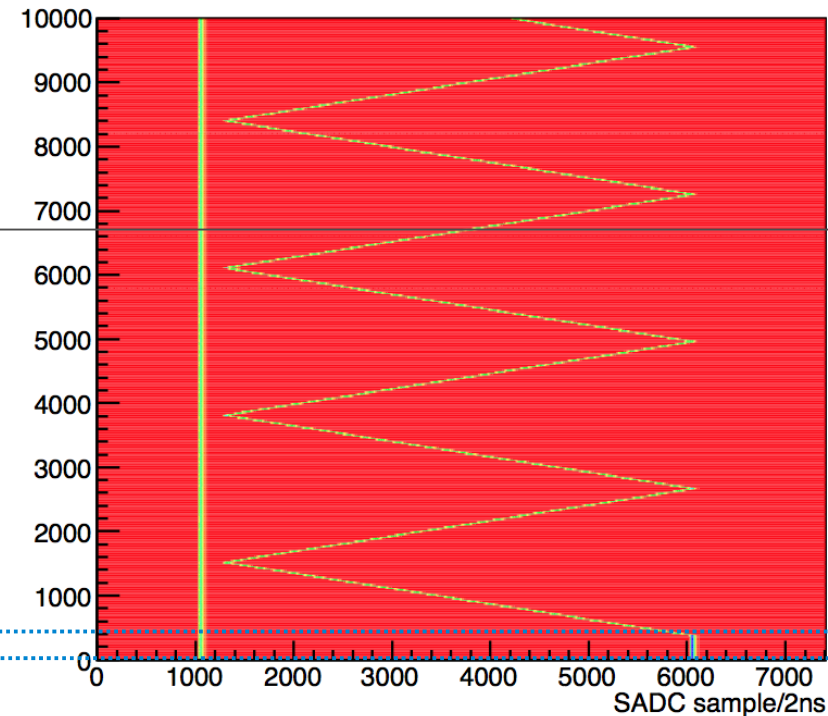
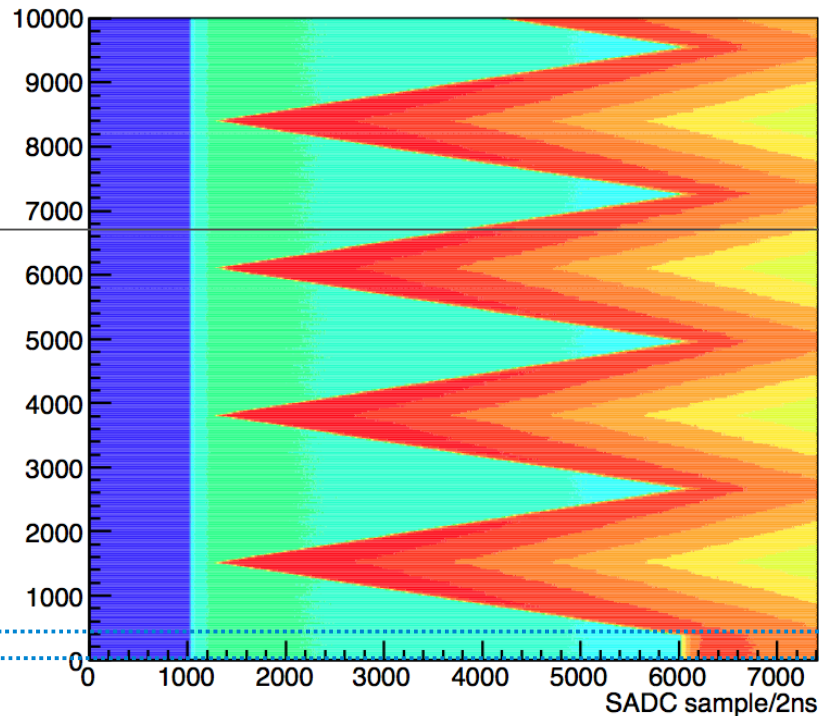
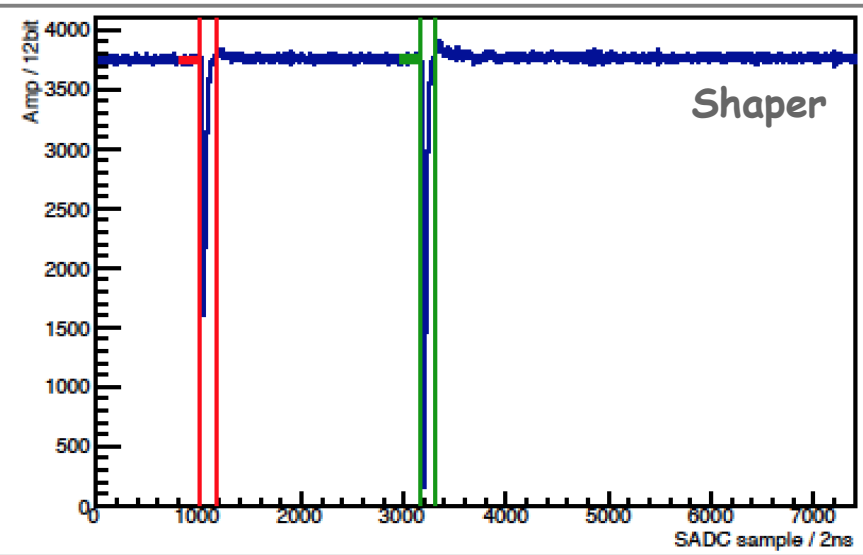
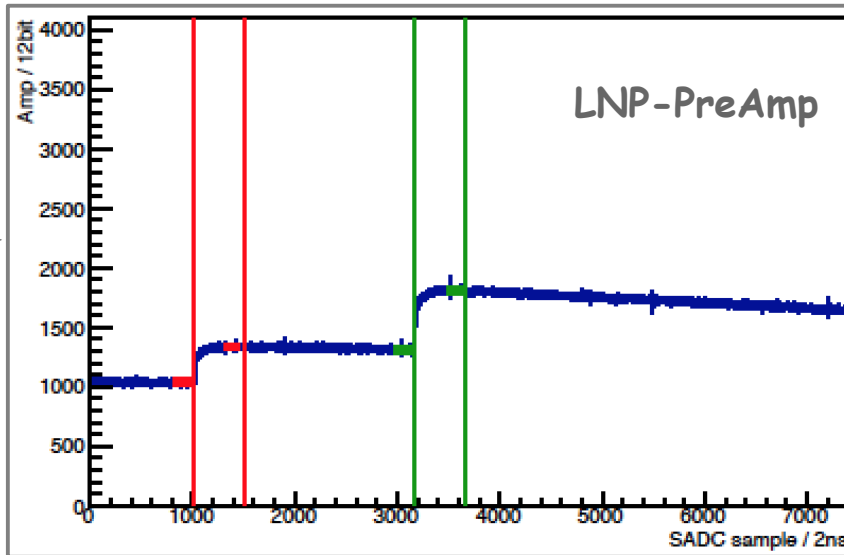
Struck 500MS/s 12bit
500MHz VME SADC



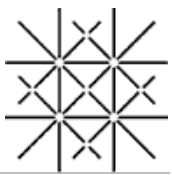
Double Burst Linearity (VPTT)



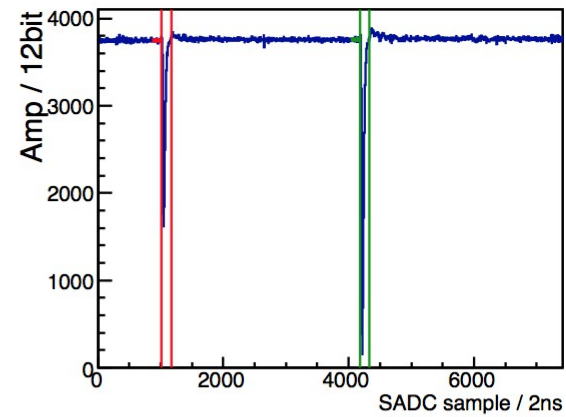
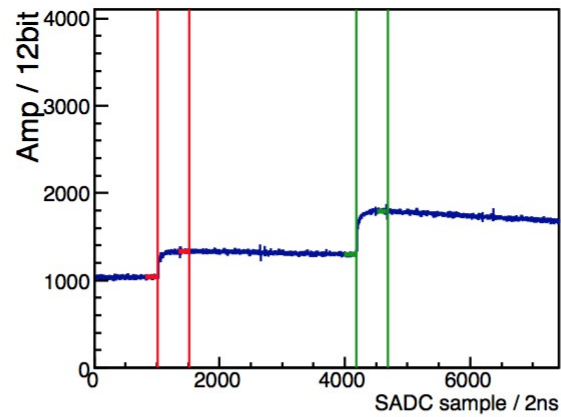
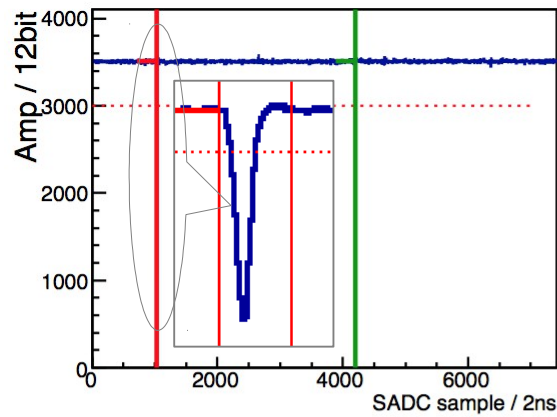
UNI
BASEL



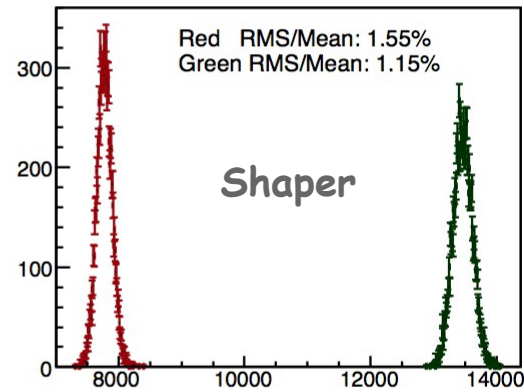
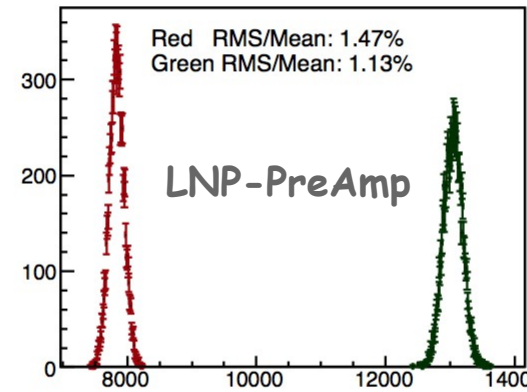
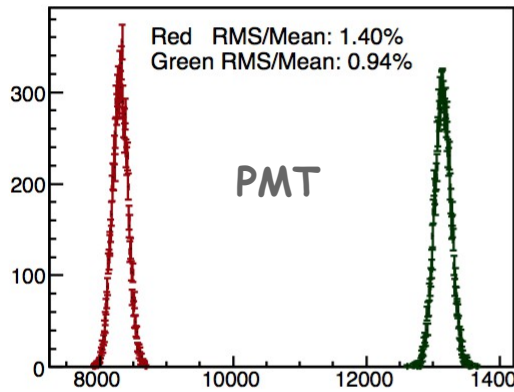
Double Burst Linearity (VPTT)



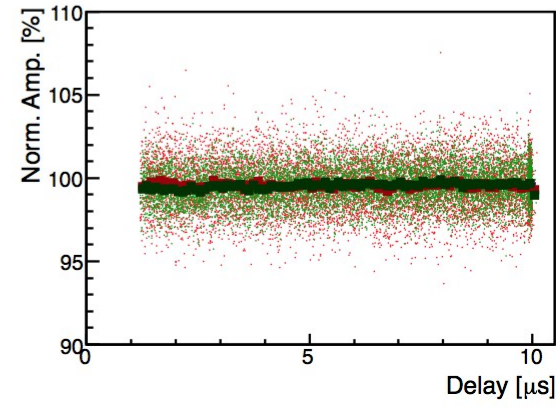
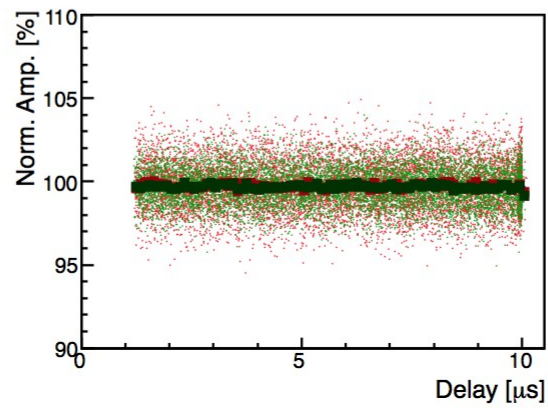
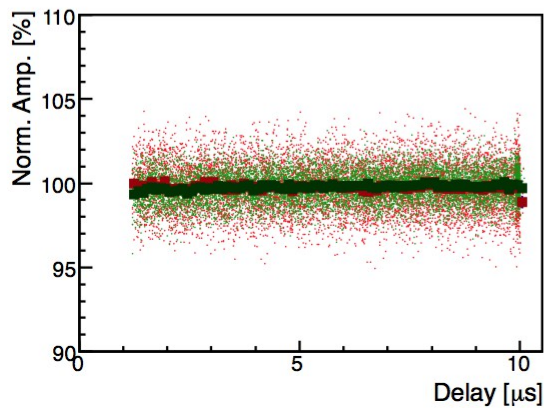
UNI
BASEL



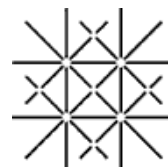
Typical
Signal



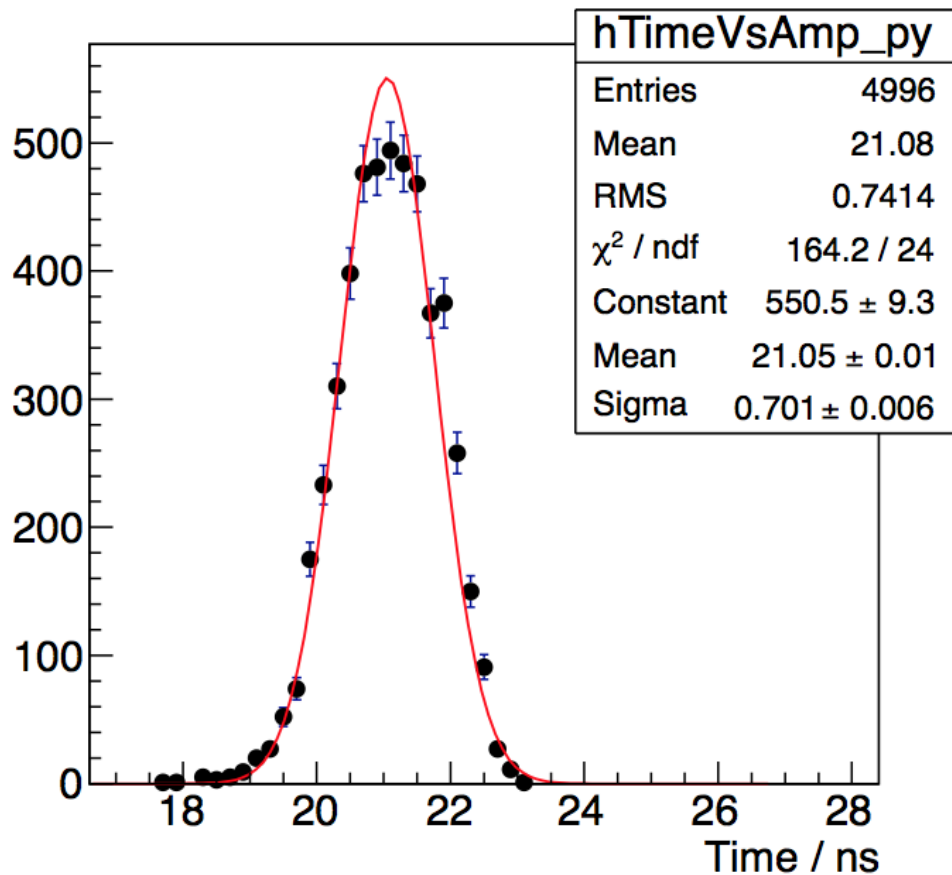
Signal
Distribution



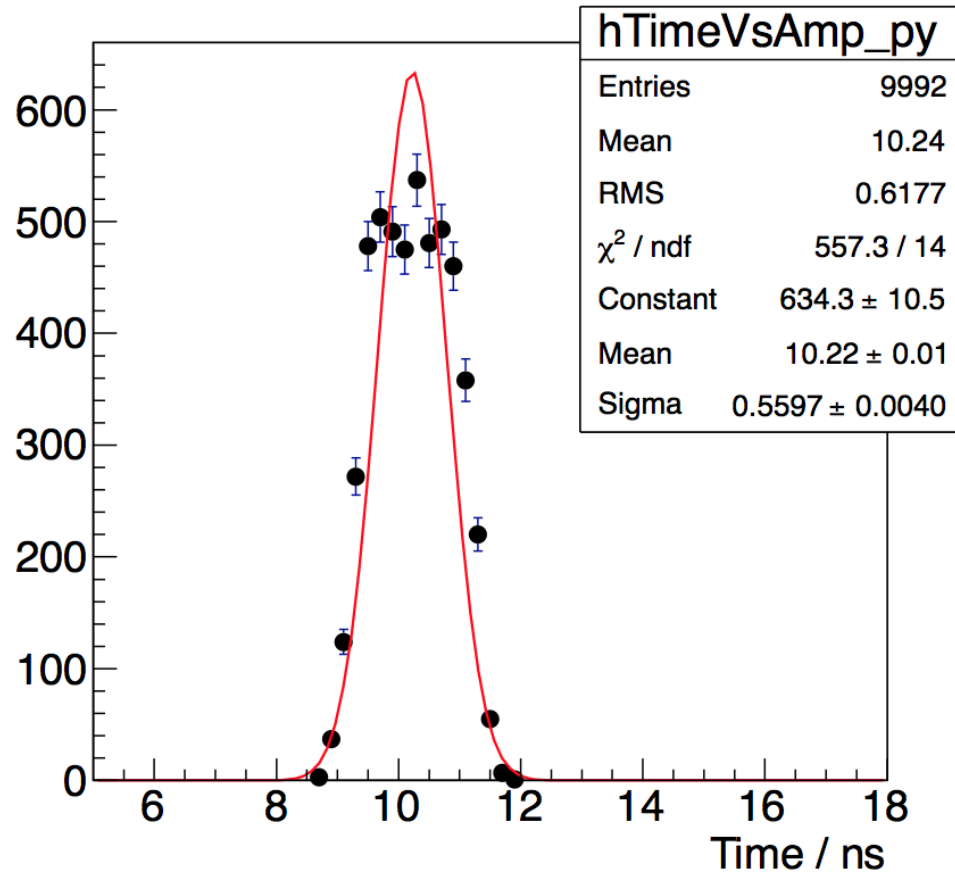
Count-rate
Stability



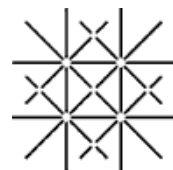
LED 1



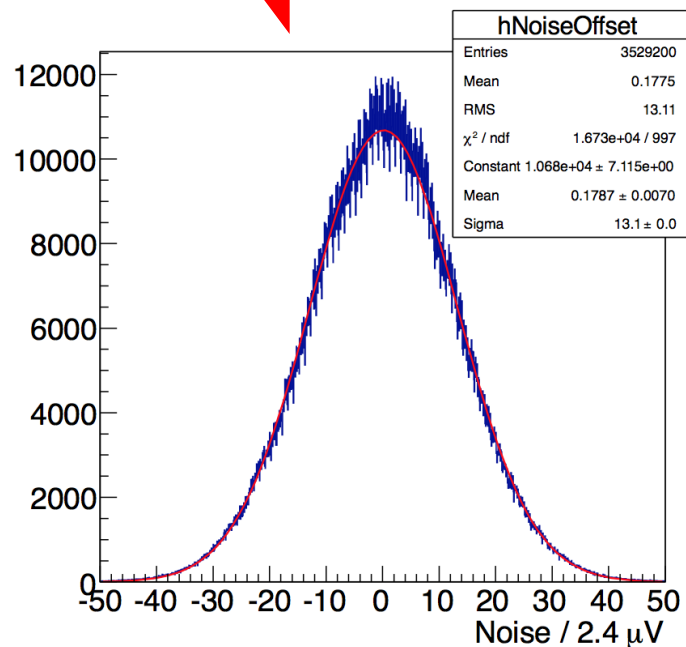
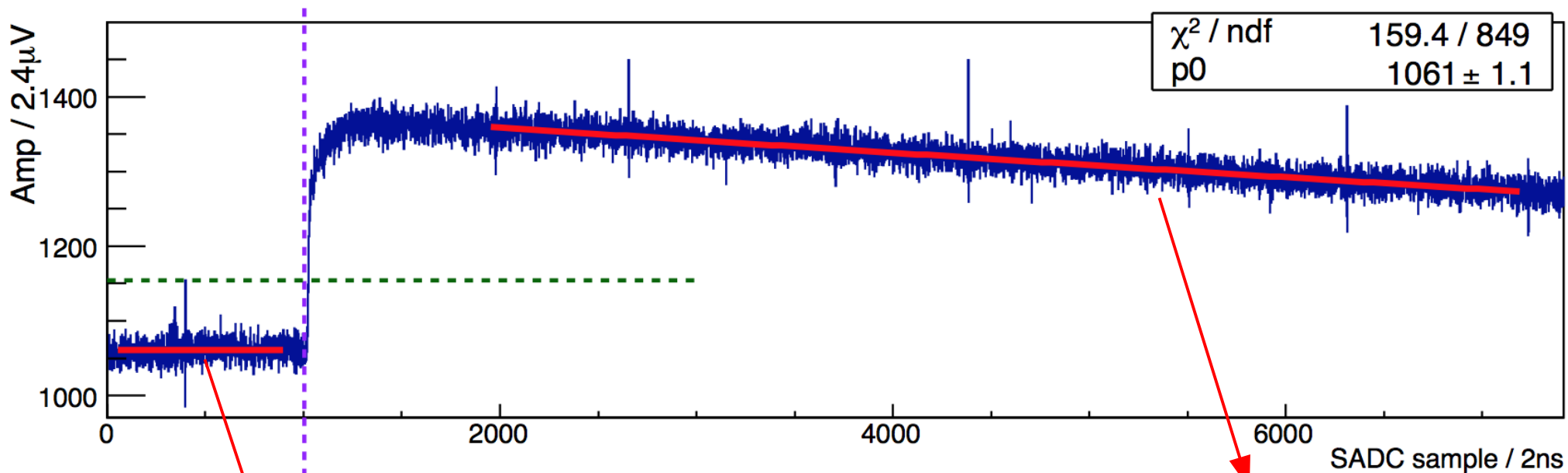
LED 2



Noise & Dynamic range (VPTT)



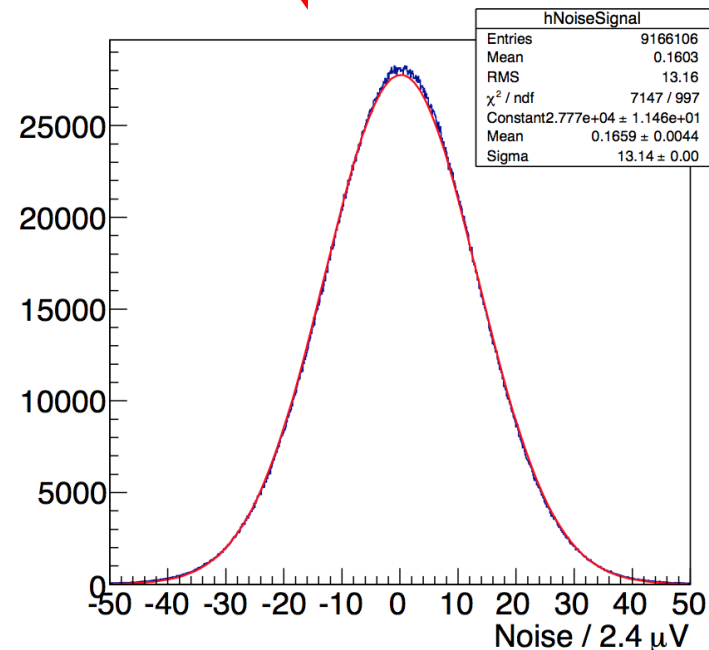
UNI
BASEL



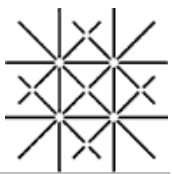
High dynamic range

$13 \times 24 \mu\text{V} \sim 310 \mu\text{V}$

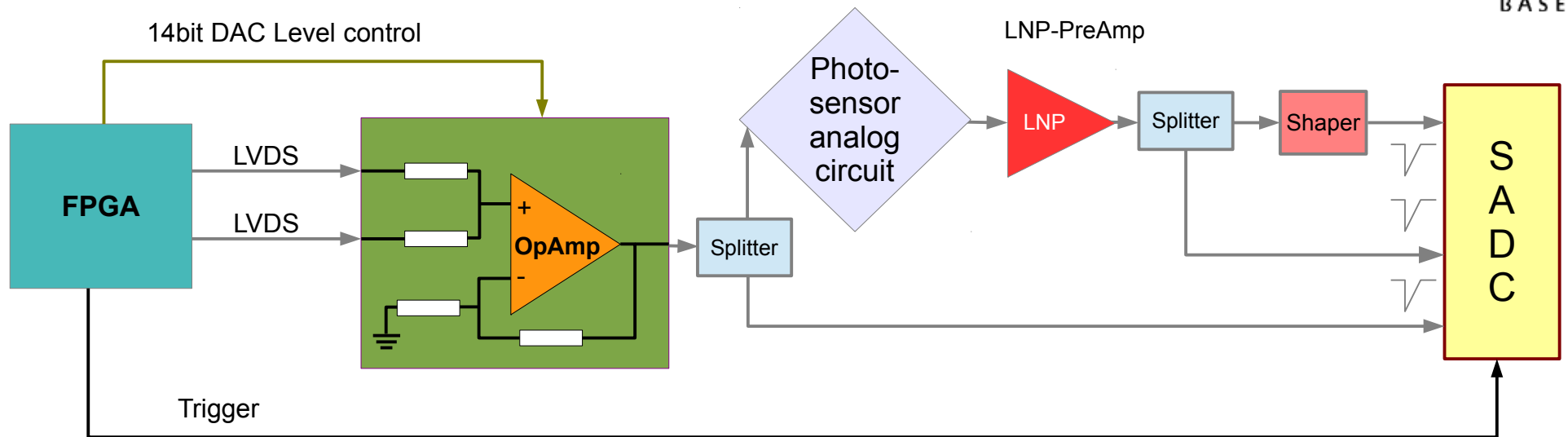
$2.5\text{V} / 310 \mu\text{V} \sim 8000$



Double Burst Linearity - Measurement Method



UNI
BASEL



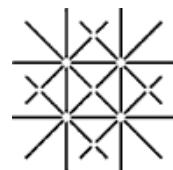
Xilinx Spartan-3AN
LED driver/signal

Small VME DAQ system
C++/ROOT based

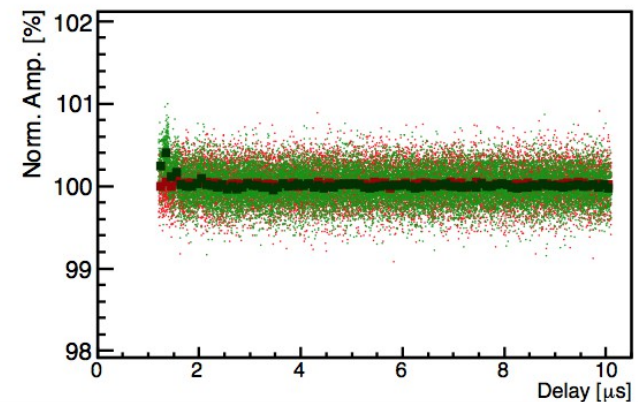
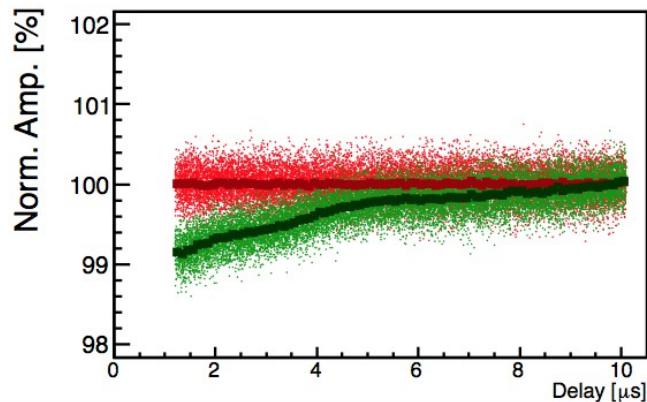
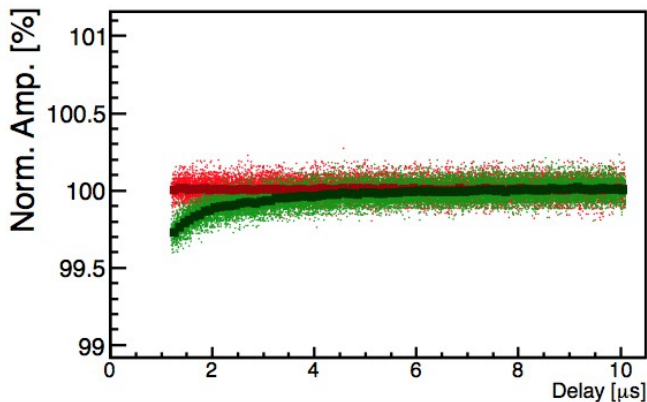
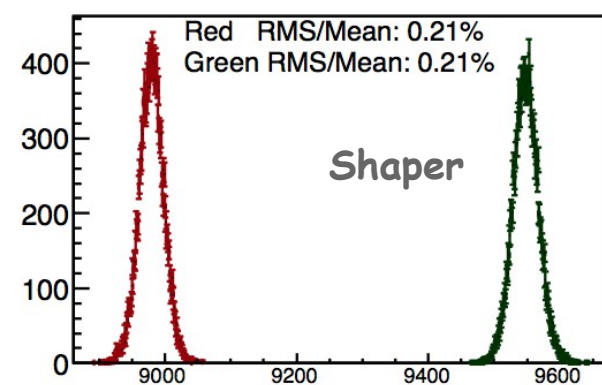
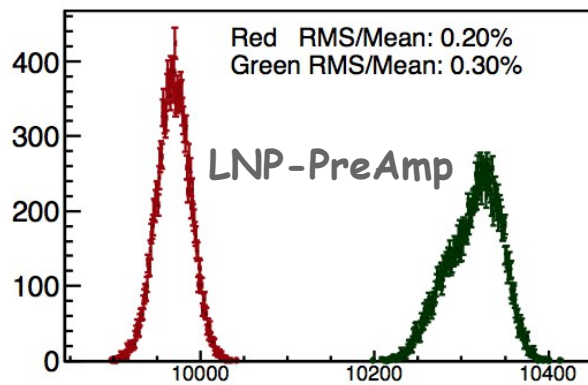
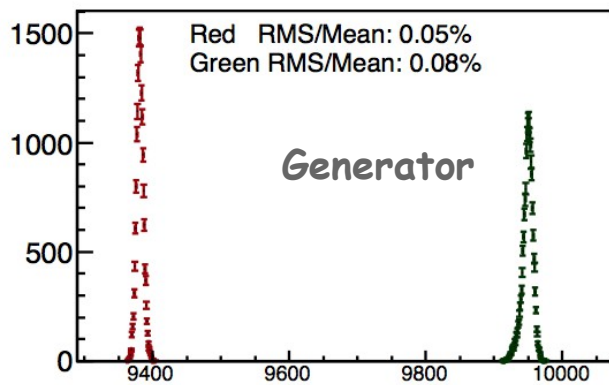
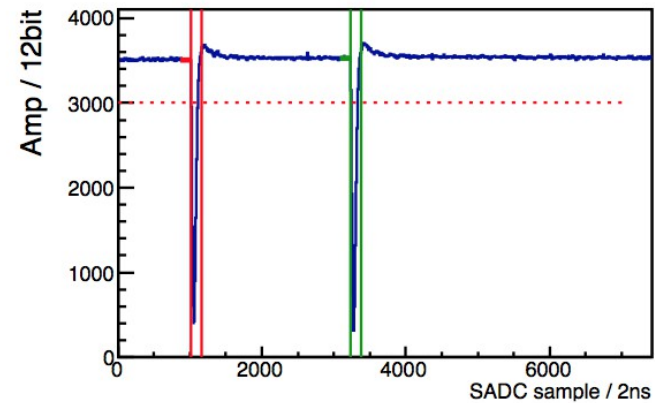
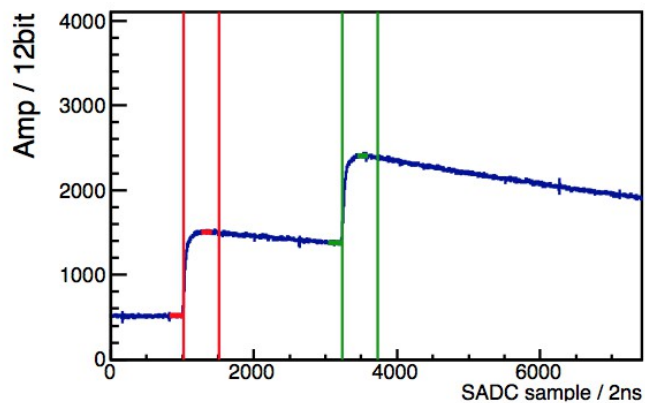
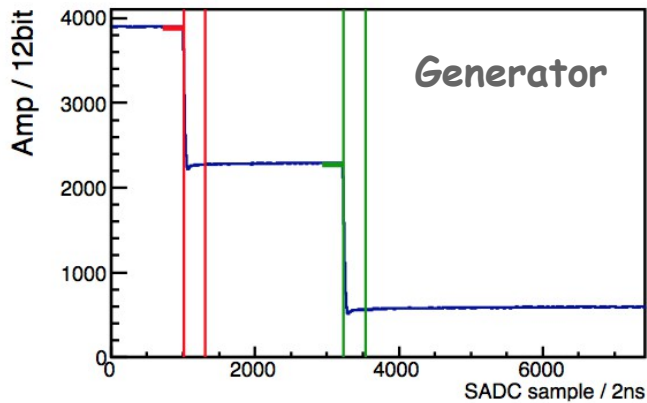
Struck 500MS/s 12bit
500MHz VME SADC

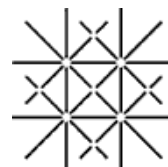


Double Burst Linearity (FPGA+OpAmp Generator)



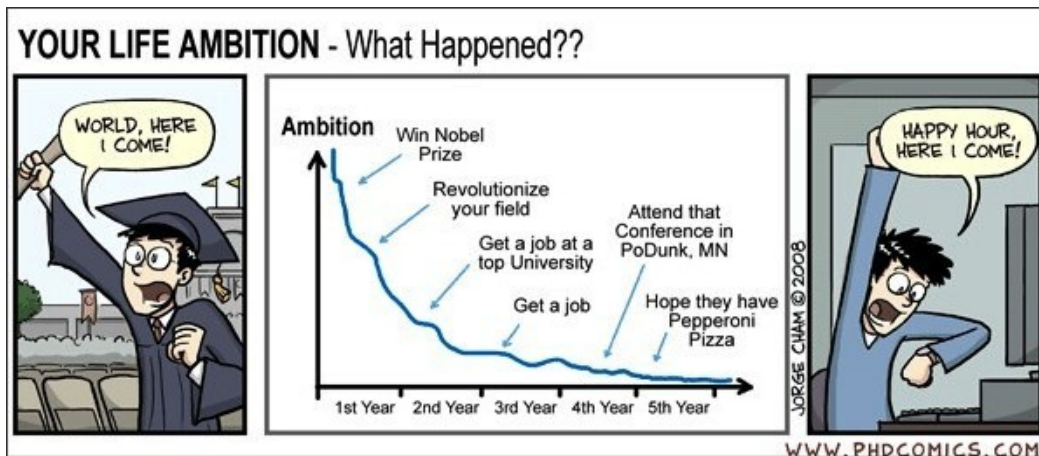
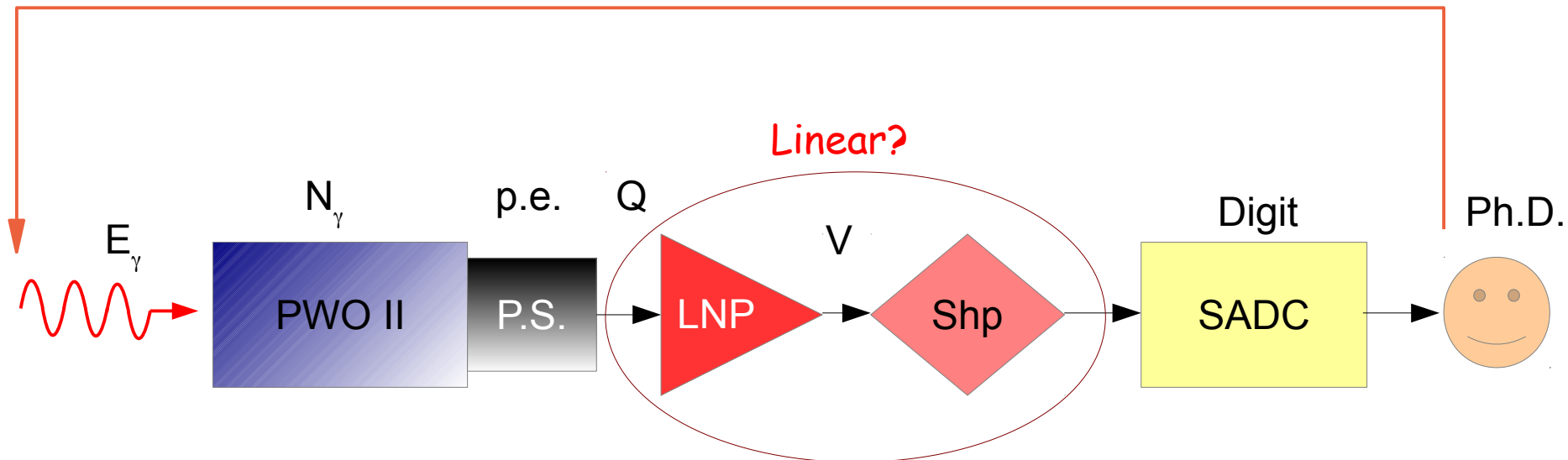
UNI
BASEL



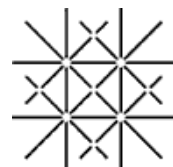


Amplitude Linearity Test

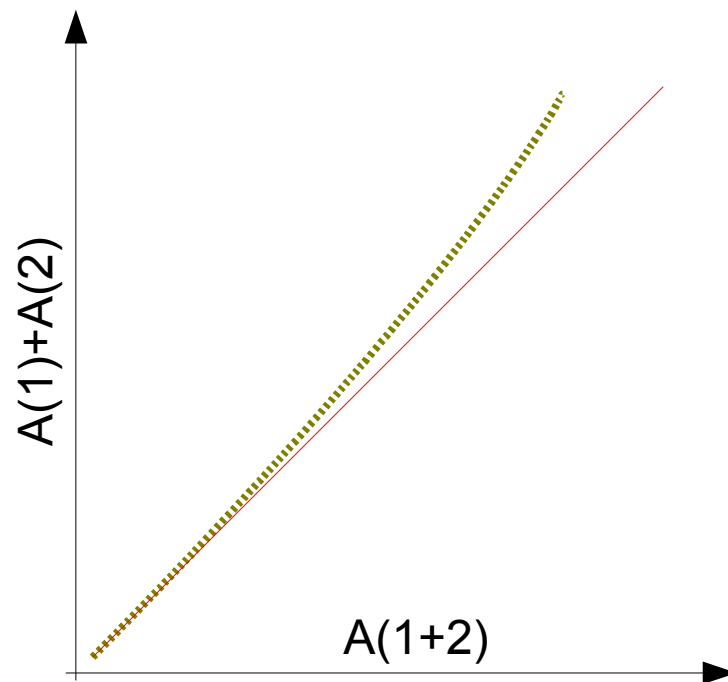
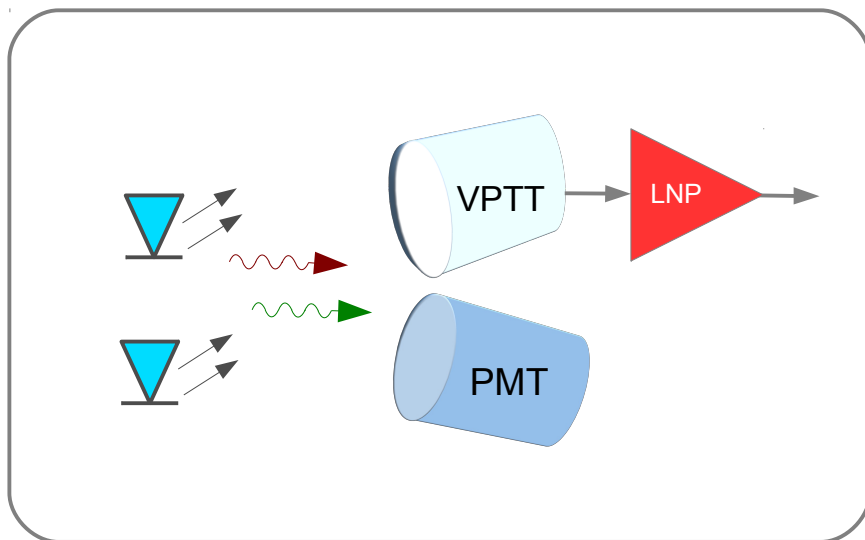
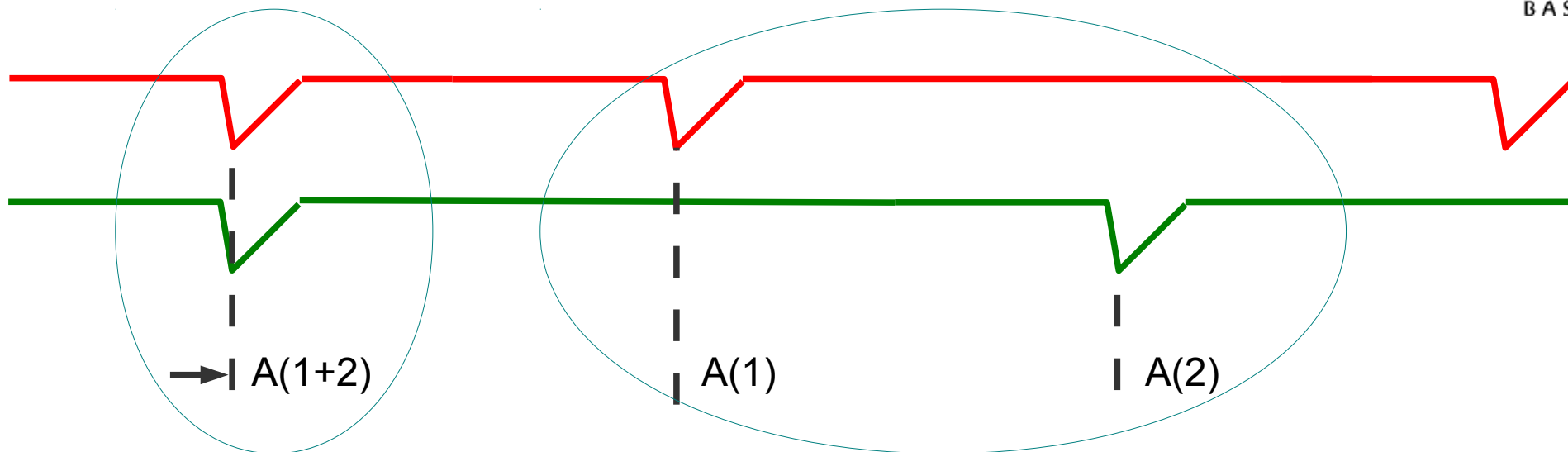
Calibration Parameter



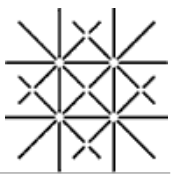
Amplitude Linearity - Measurement Method



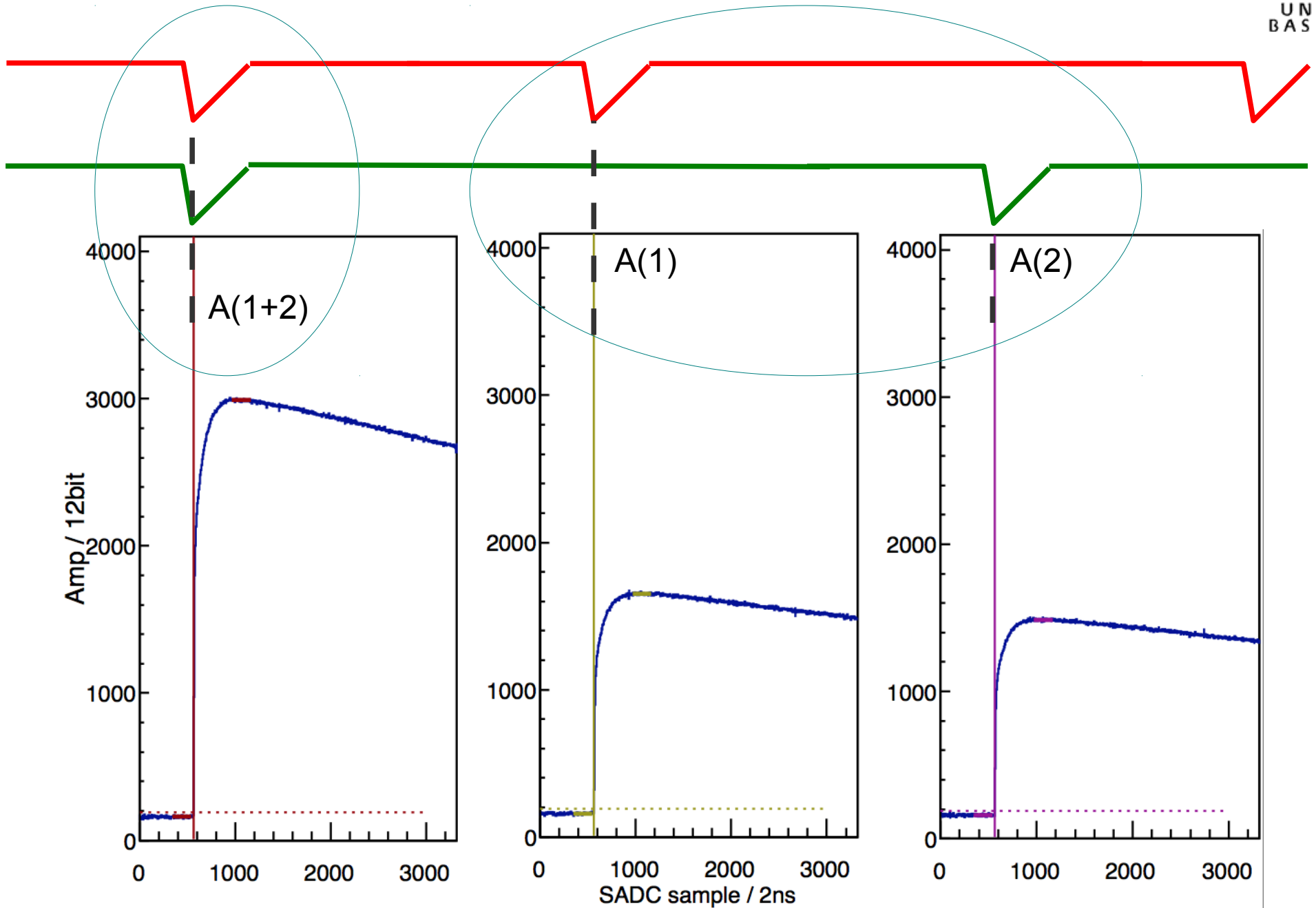
UNI
BASEL



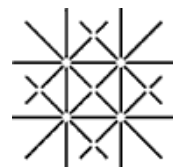
Amplitude Linearity - Typical Signals



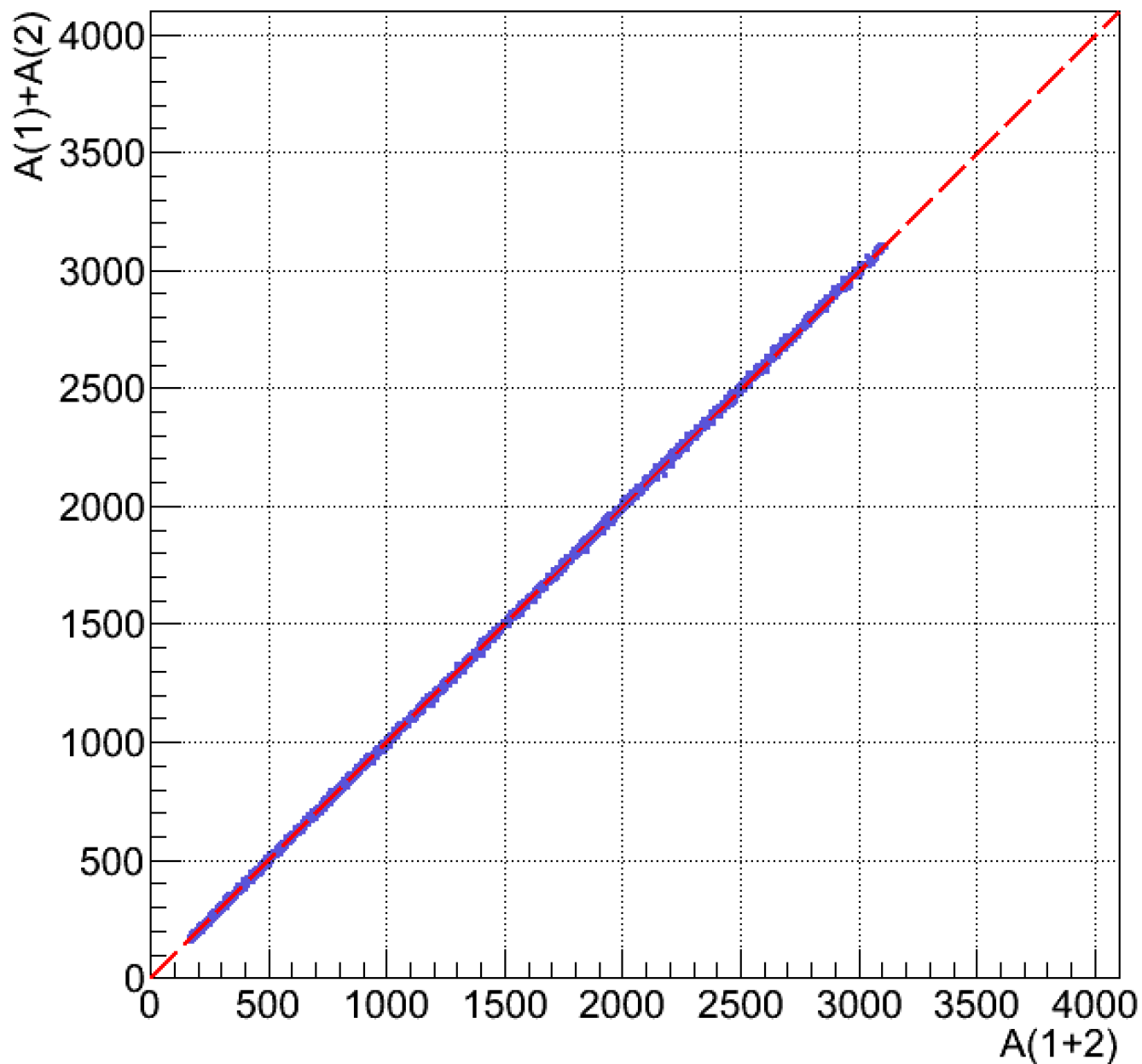
UNI
BASEL



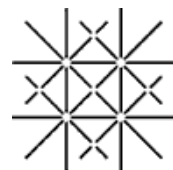
Amplitude Linearity



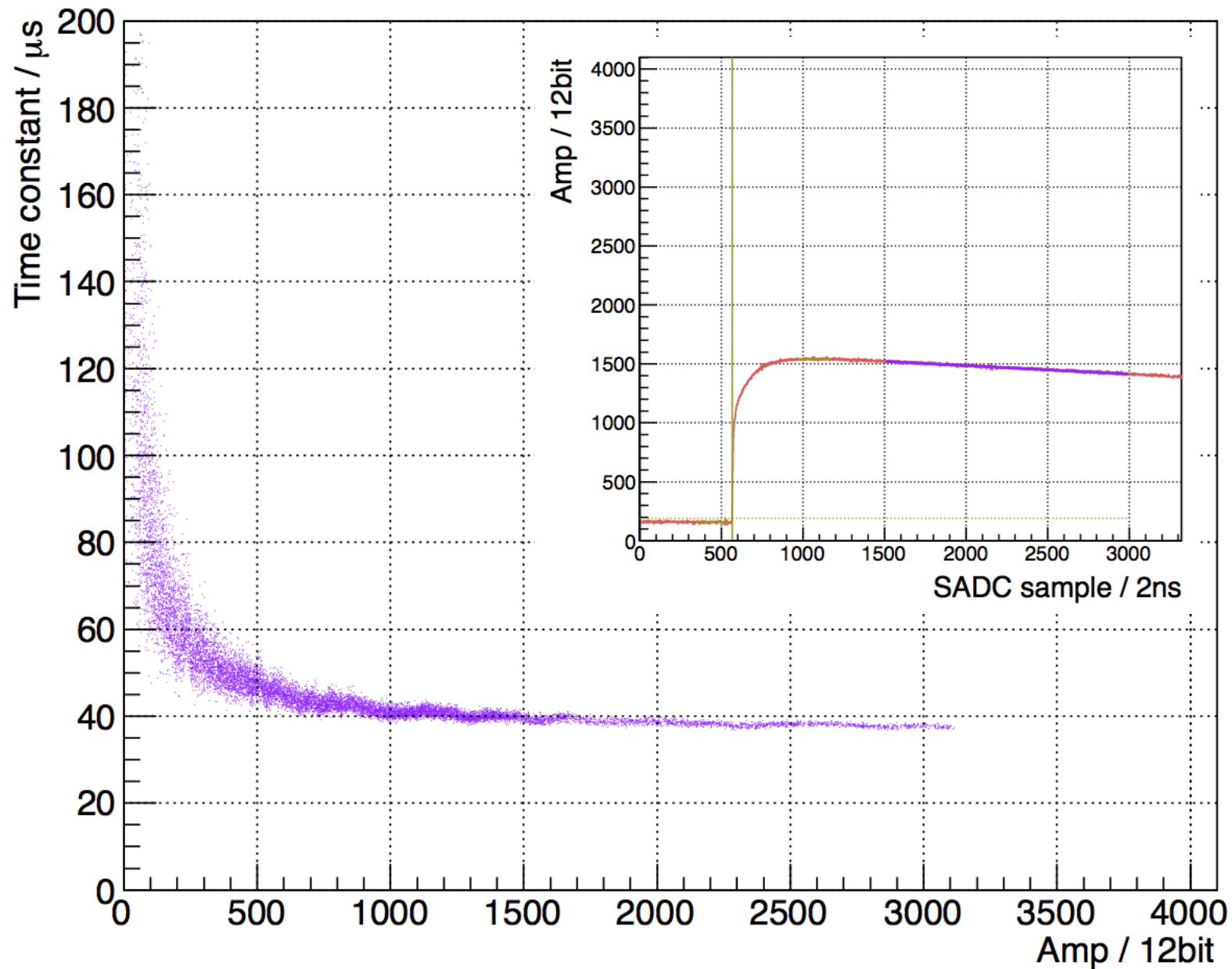
UNI
BASEL



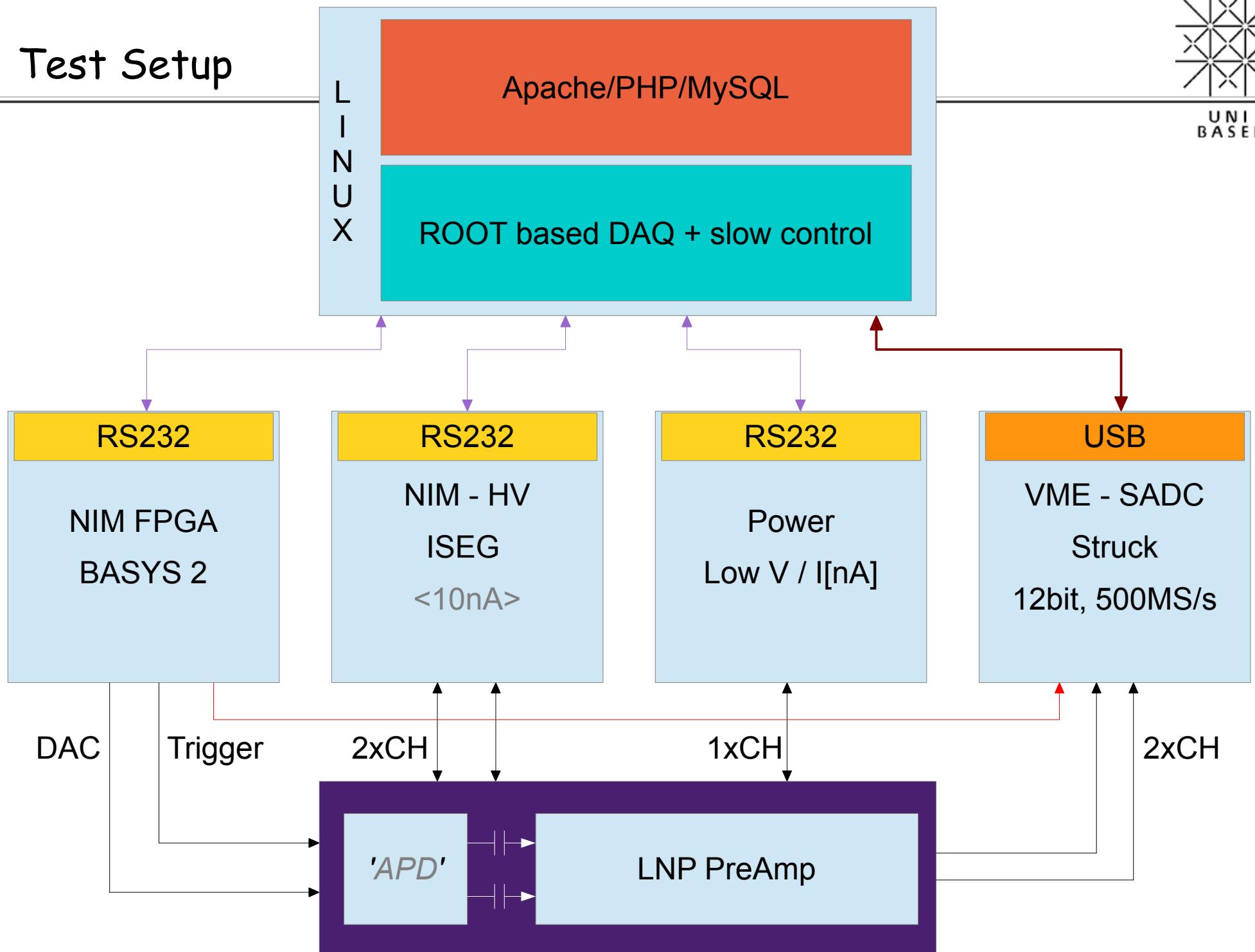
Time constant Vs Amplitude



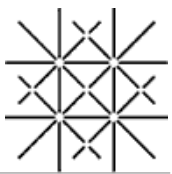
UNI
BASEL



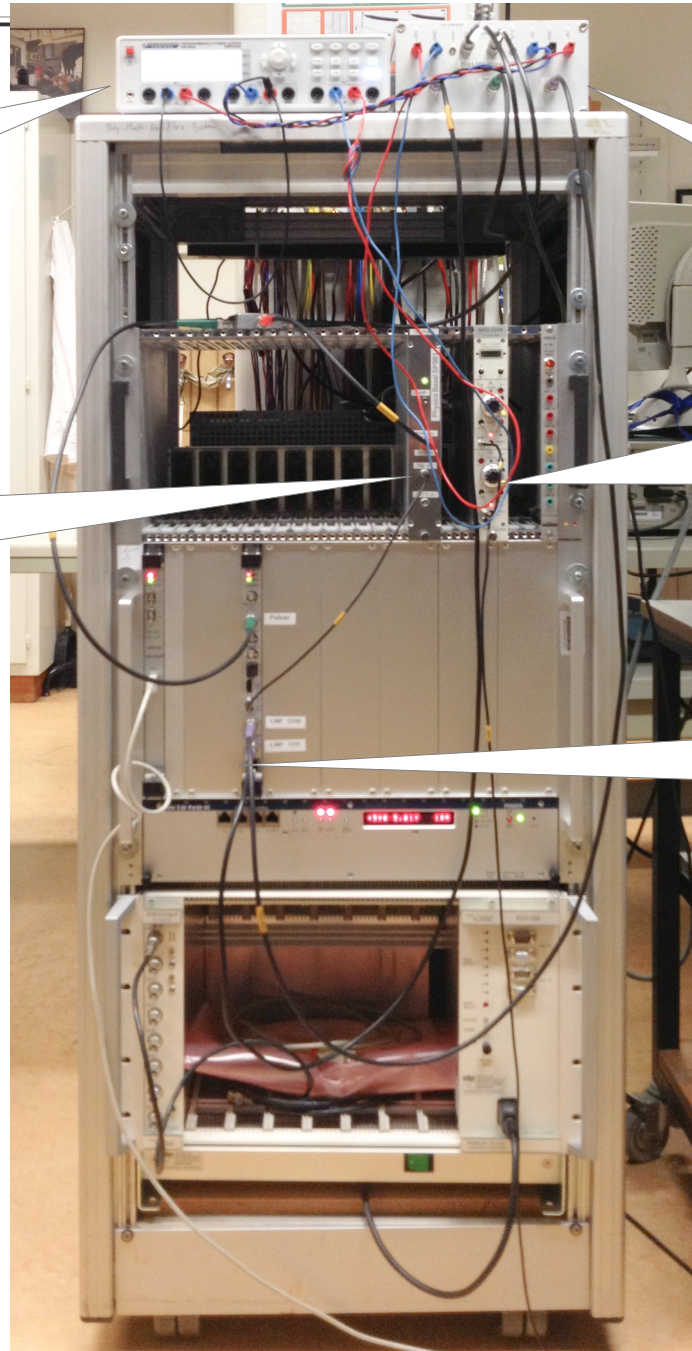
Test Setup



Test Rack



UNI
BASEL



Low Voltage
Supply

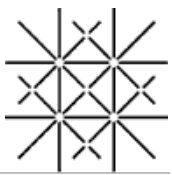
Test Box

FPGA
Generator

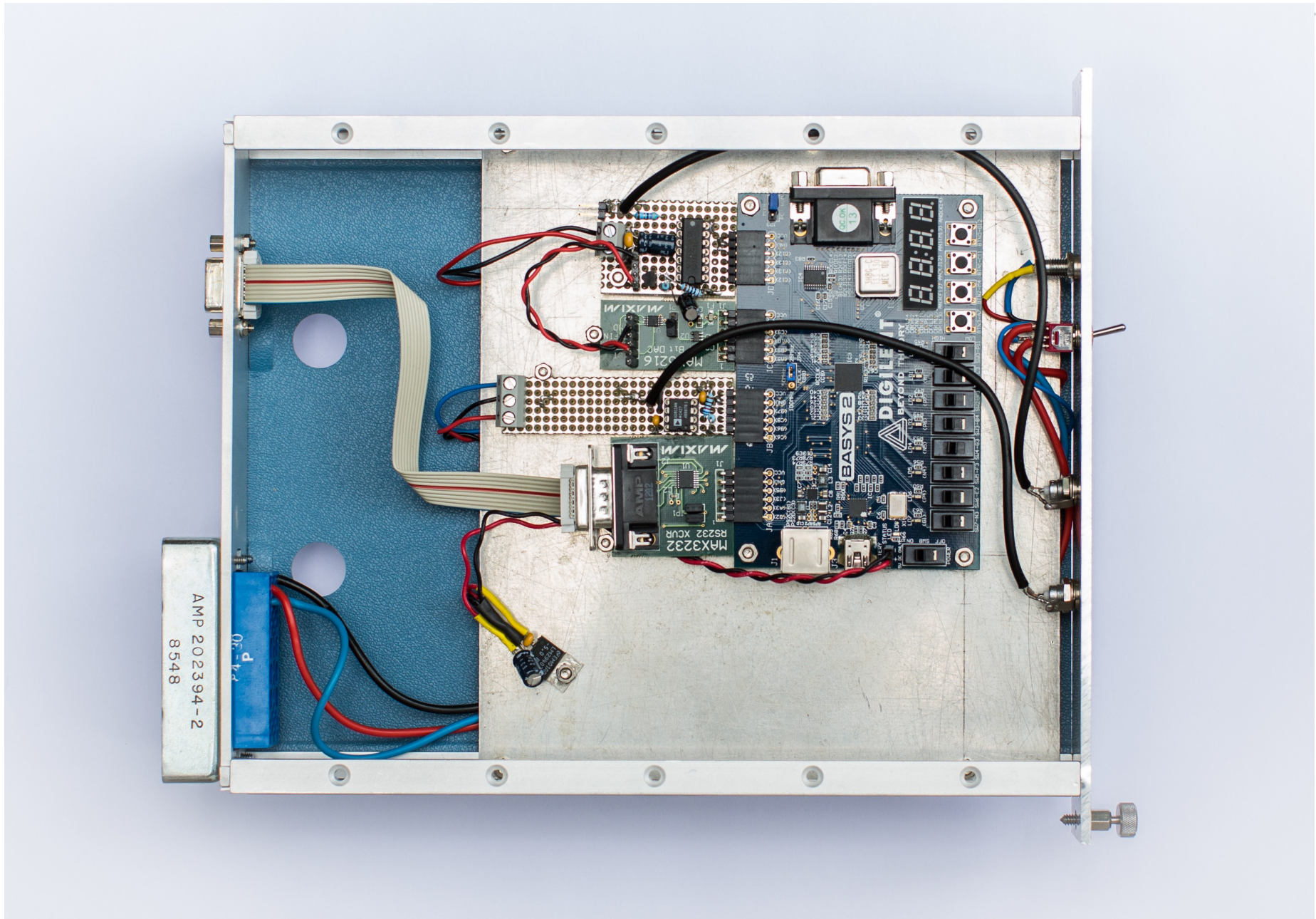
High Voltage
Supply

Struck 500MS/s
12bit SADC

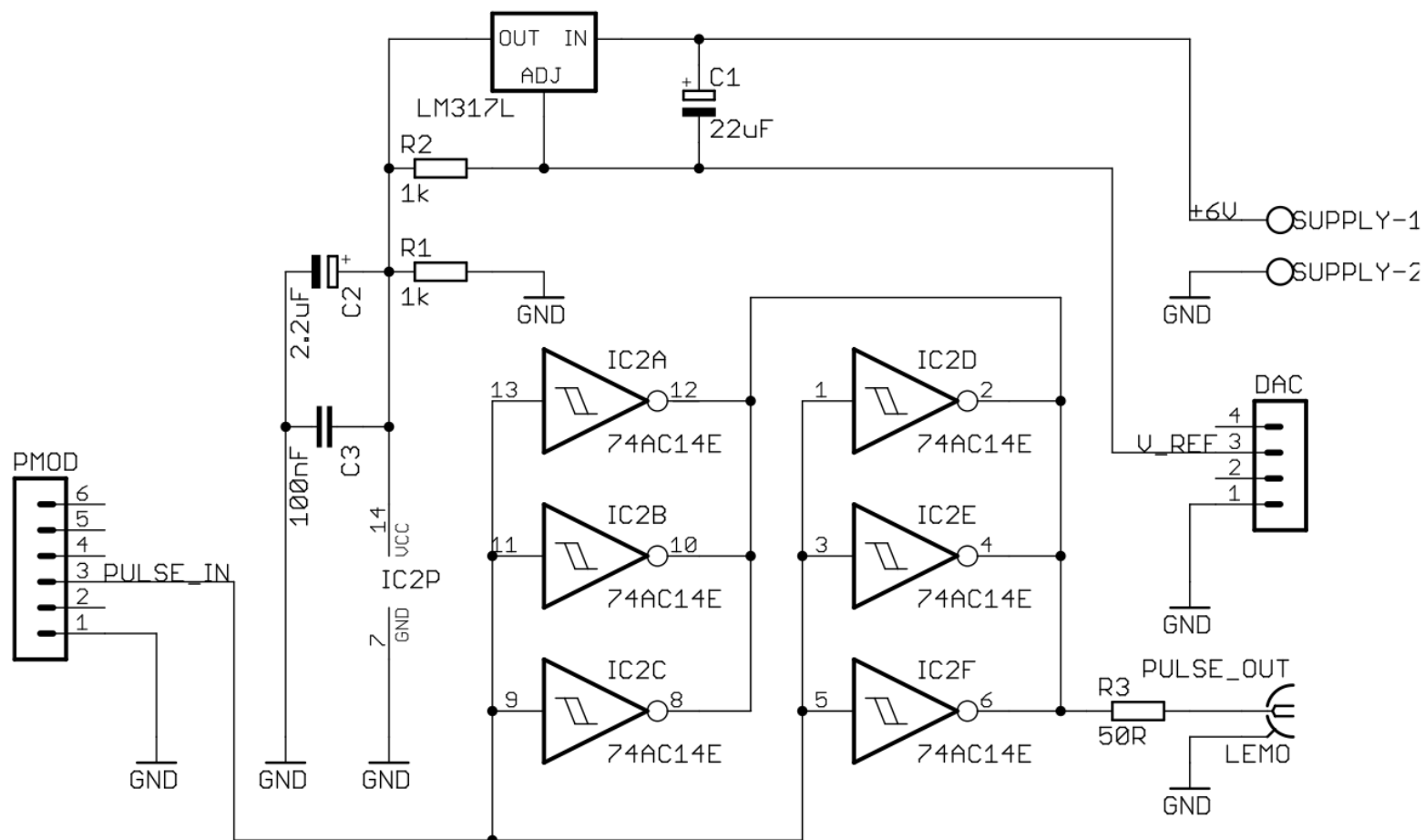
FPGA Generator



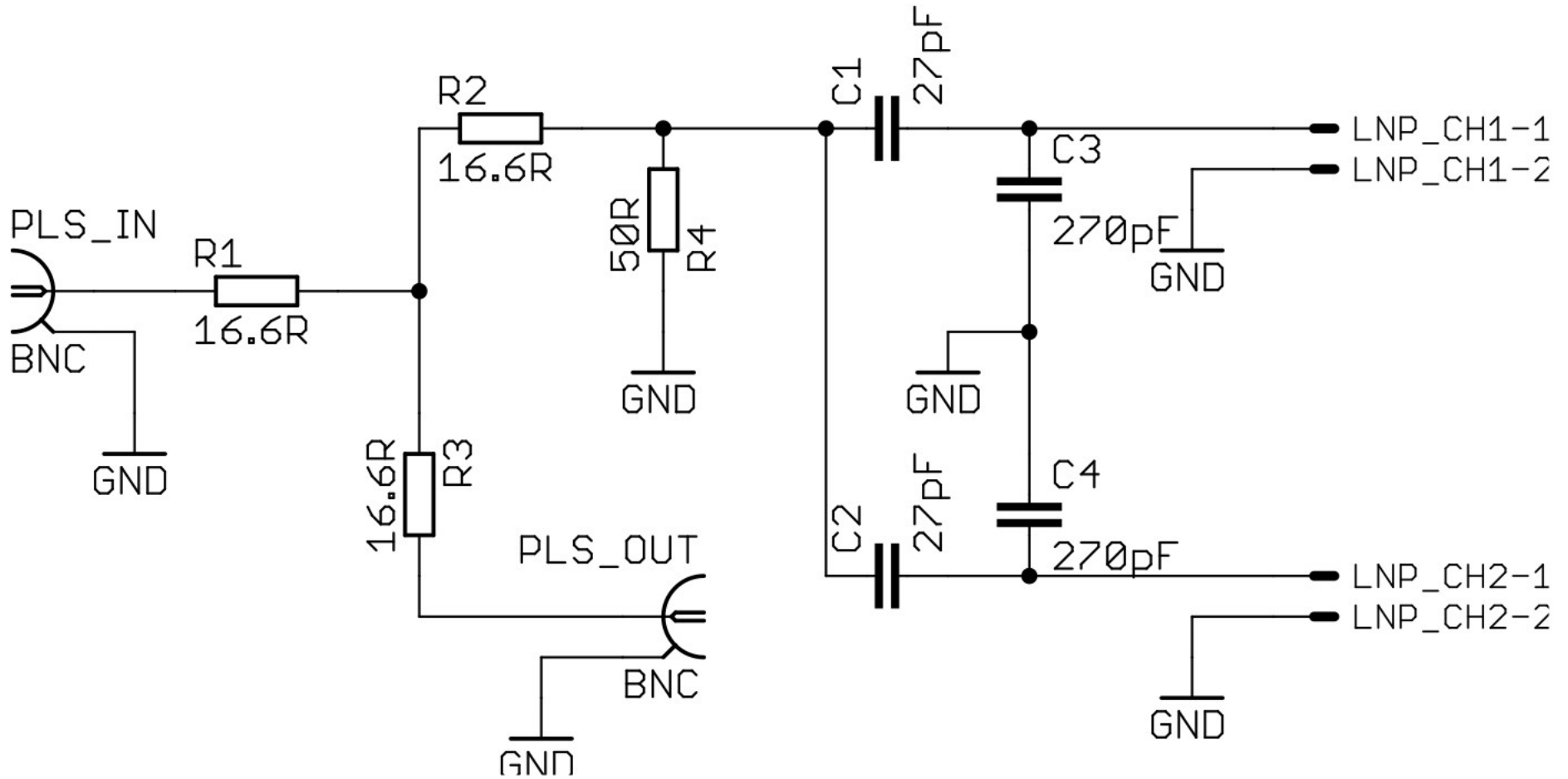
UNI
ASEL



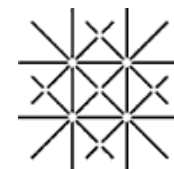
$$V_{out} = V_{DAC} + 1.25V$$



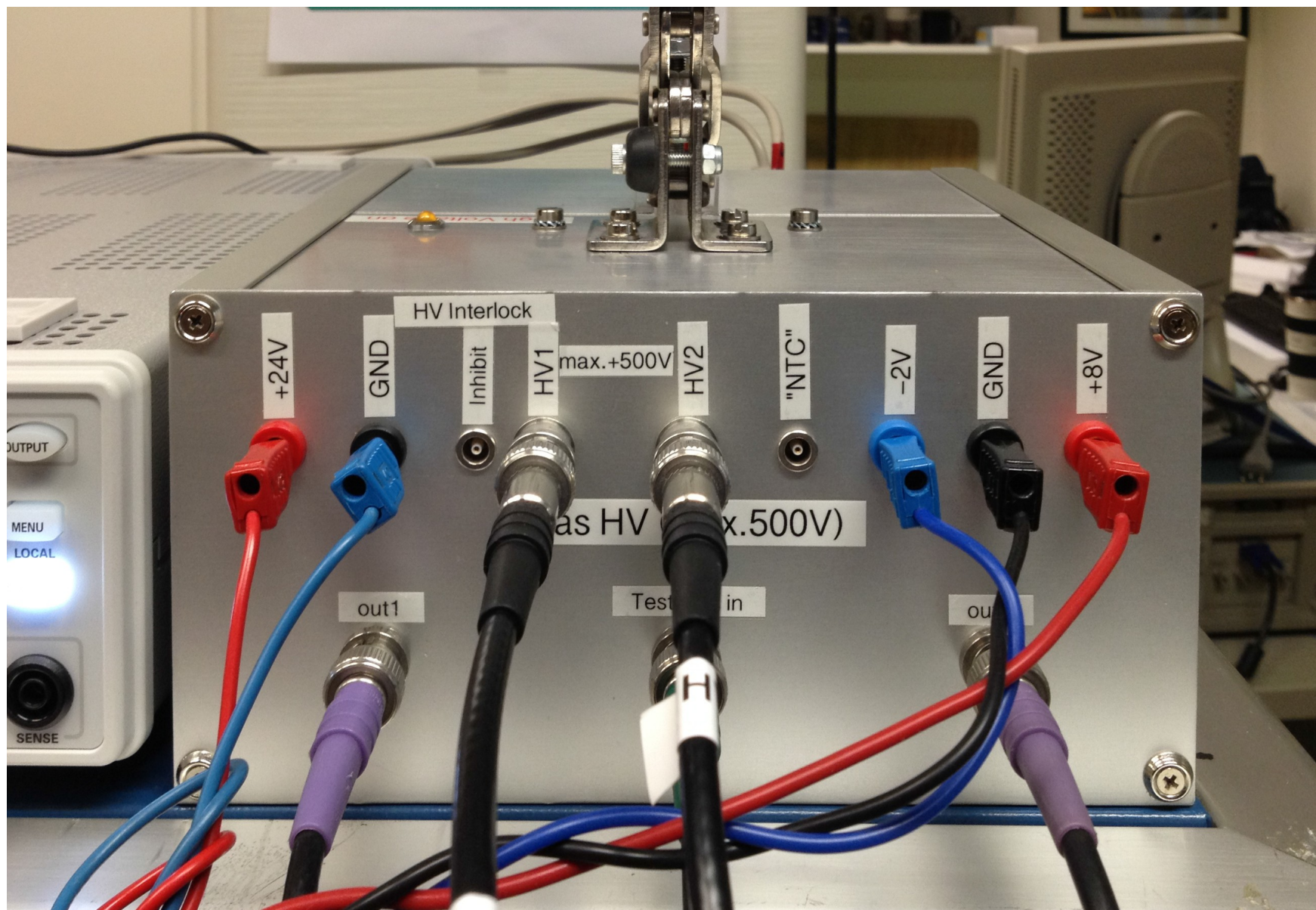
Input Coupling



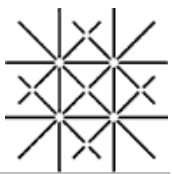
Test Box



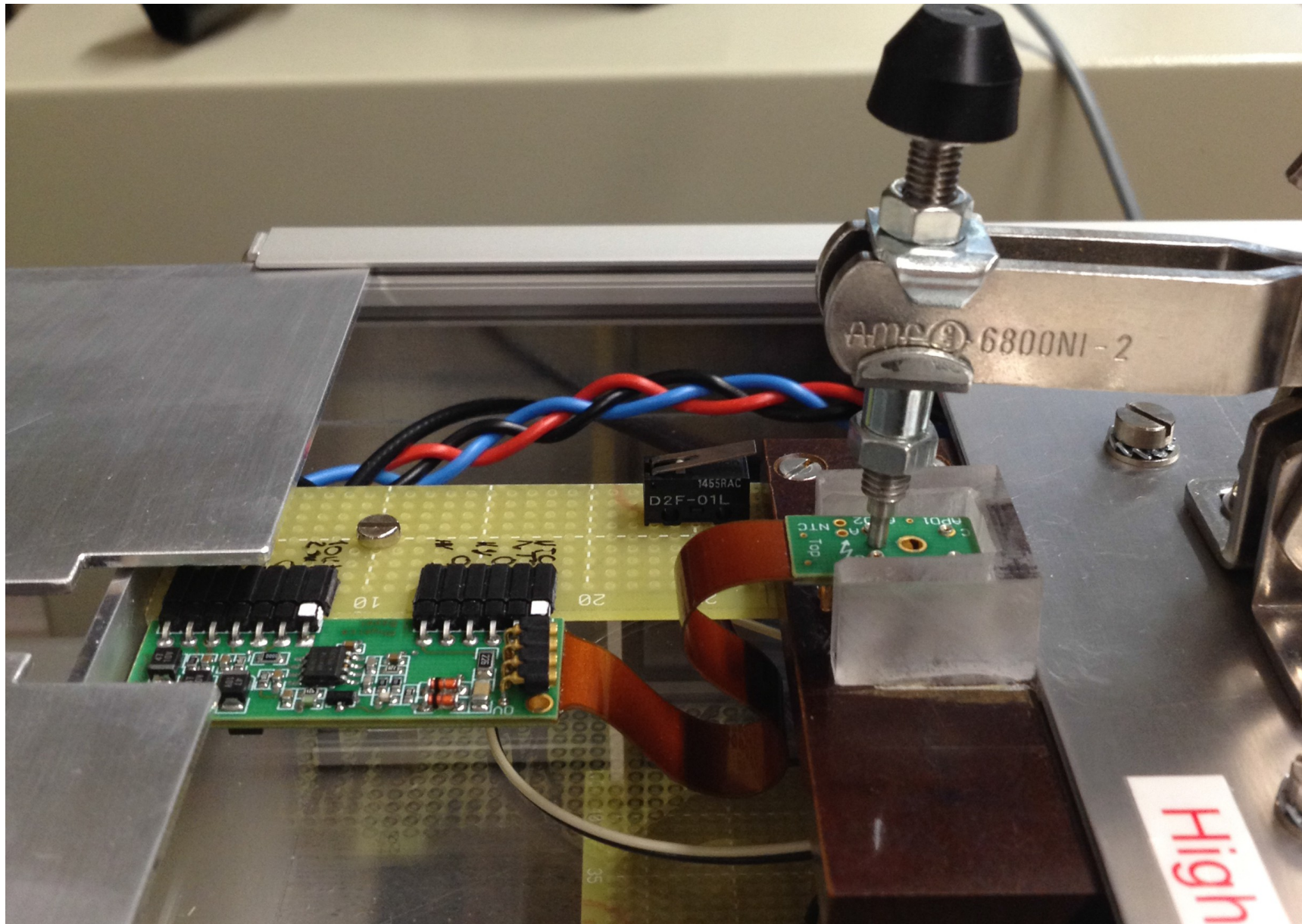
UNI
BASEL



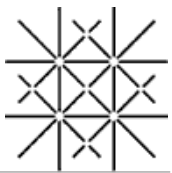
Test Box



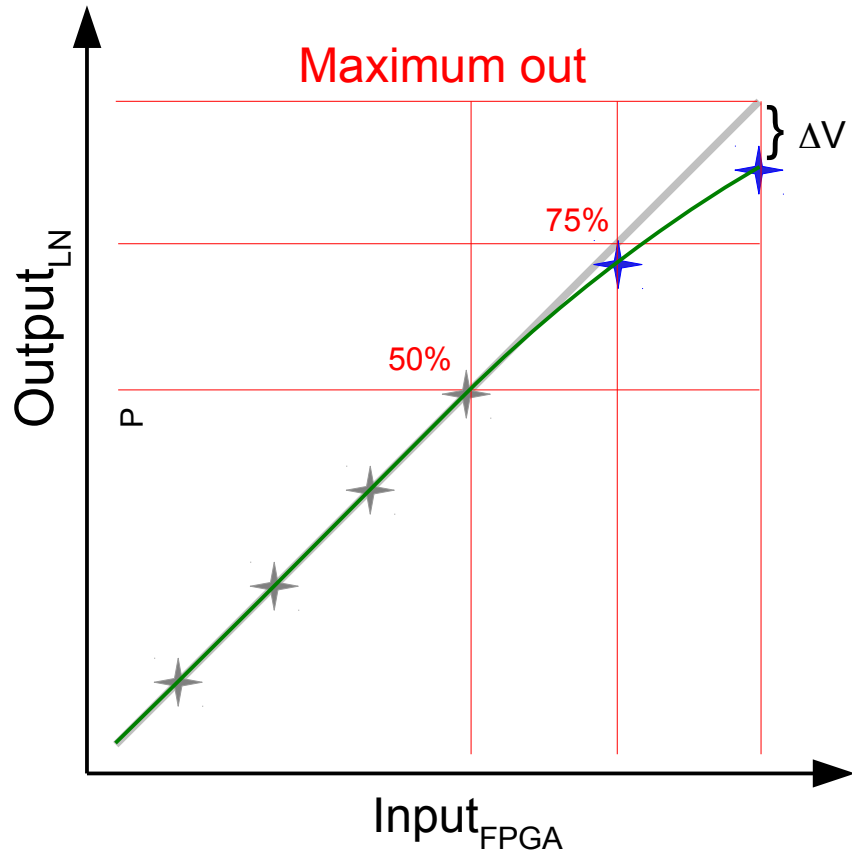
UNI
BASEL



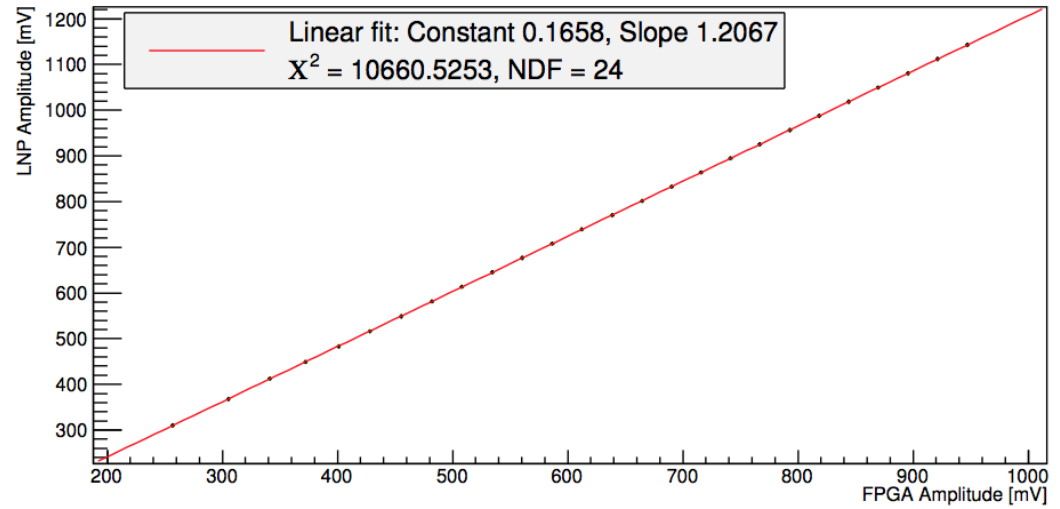
Linearity Test



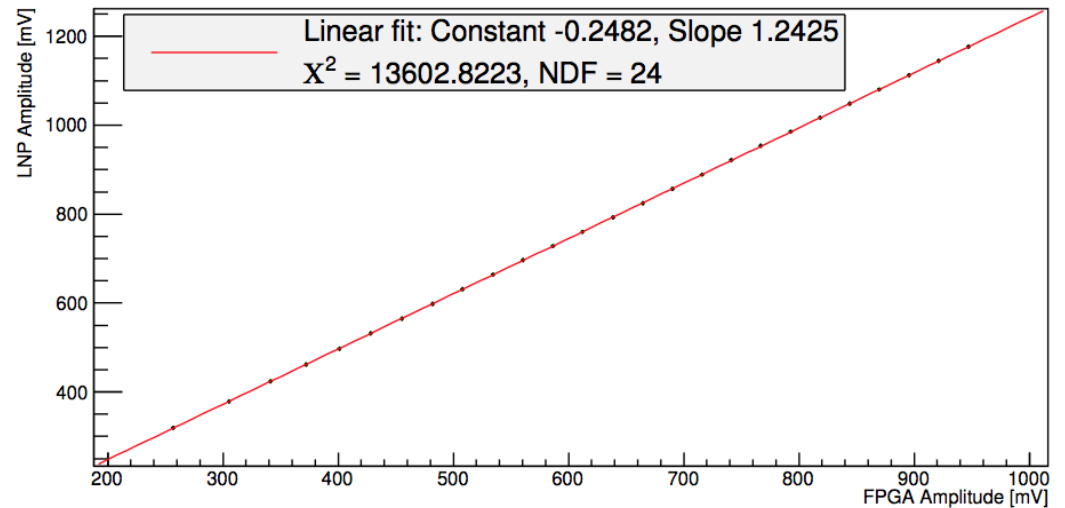
UNI
BASEL



Amplitude Distribution Fit of CH1

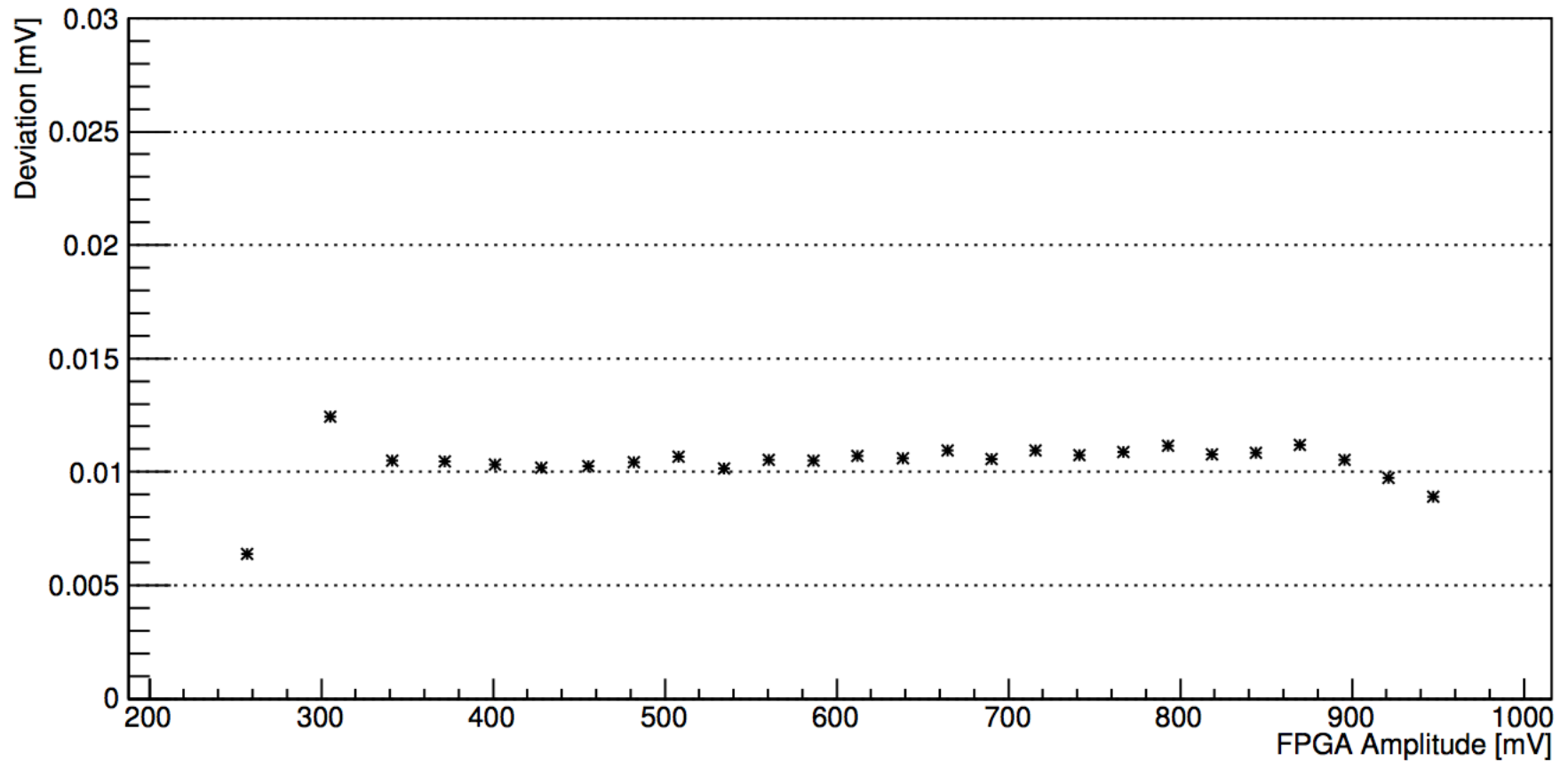


Amplitude Distribution Fit of CH2



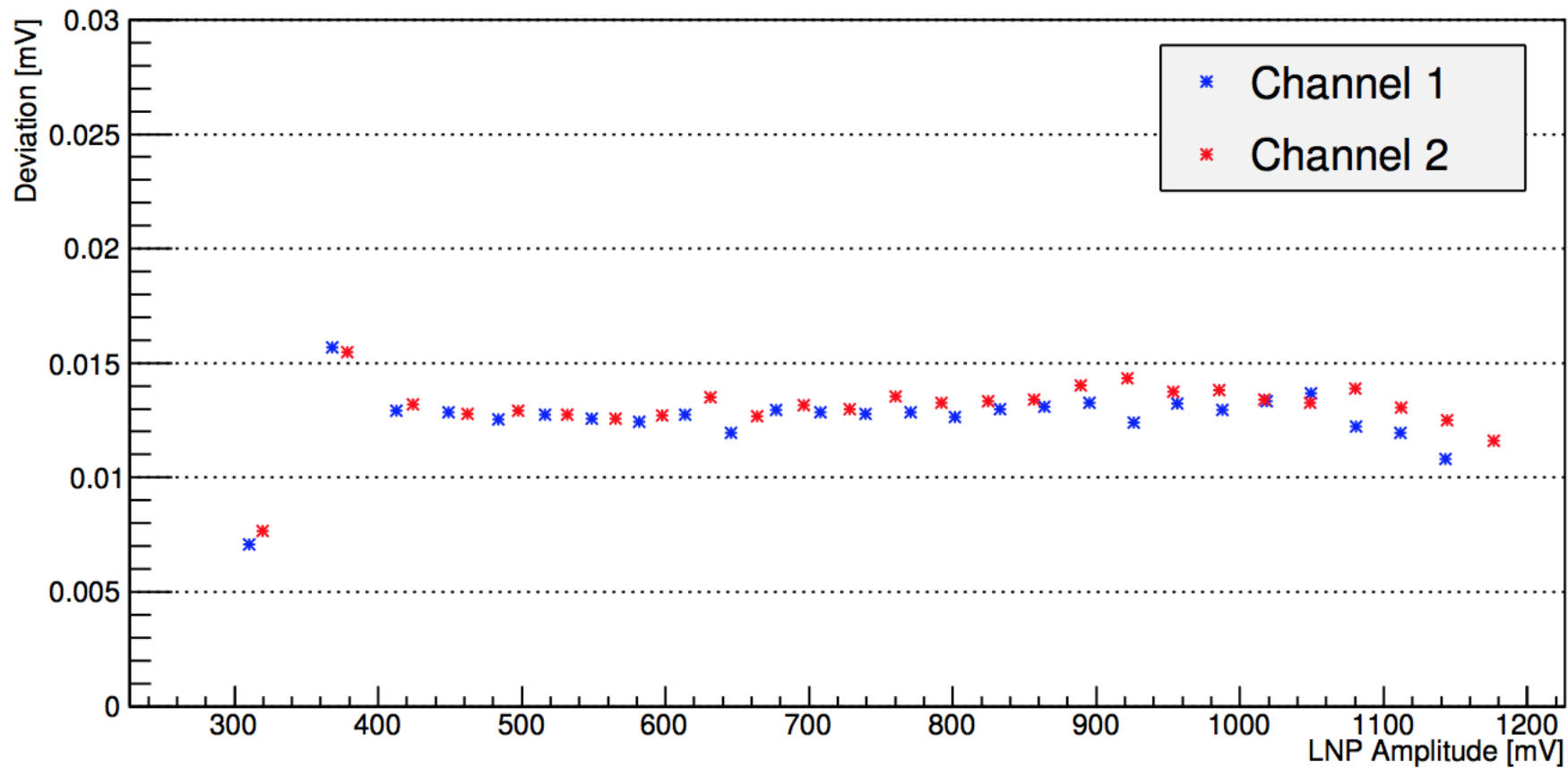
Almost constant over full range - $10\mu V$

Standard Deviation of the FPGA Signal



$$StDev_{LNP} = \sqrt{0.013^2 - 0.01^2} \approx 0.008mV$$

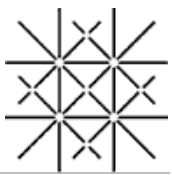
Standard Deviation of the LNP Signal



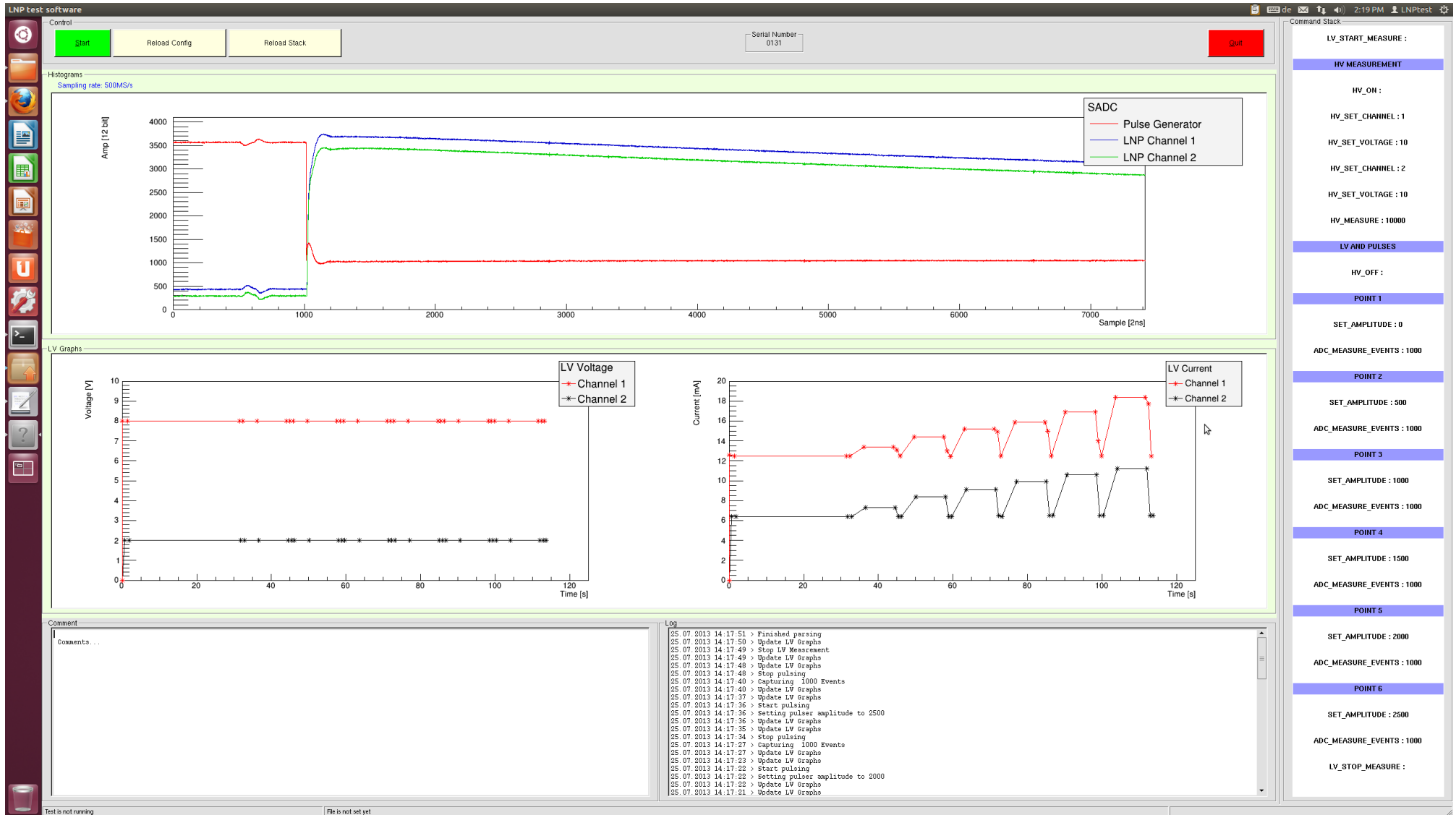
Laboratory for Serial Tests



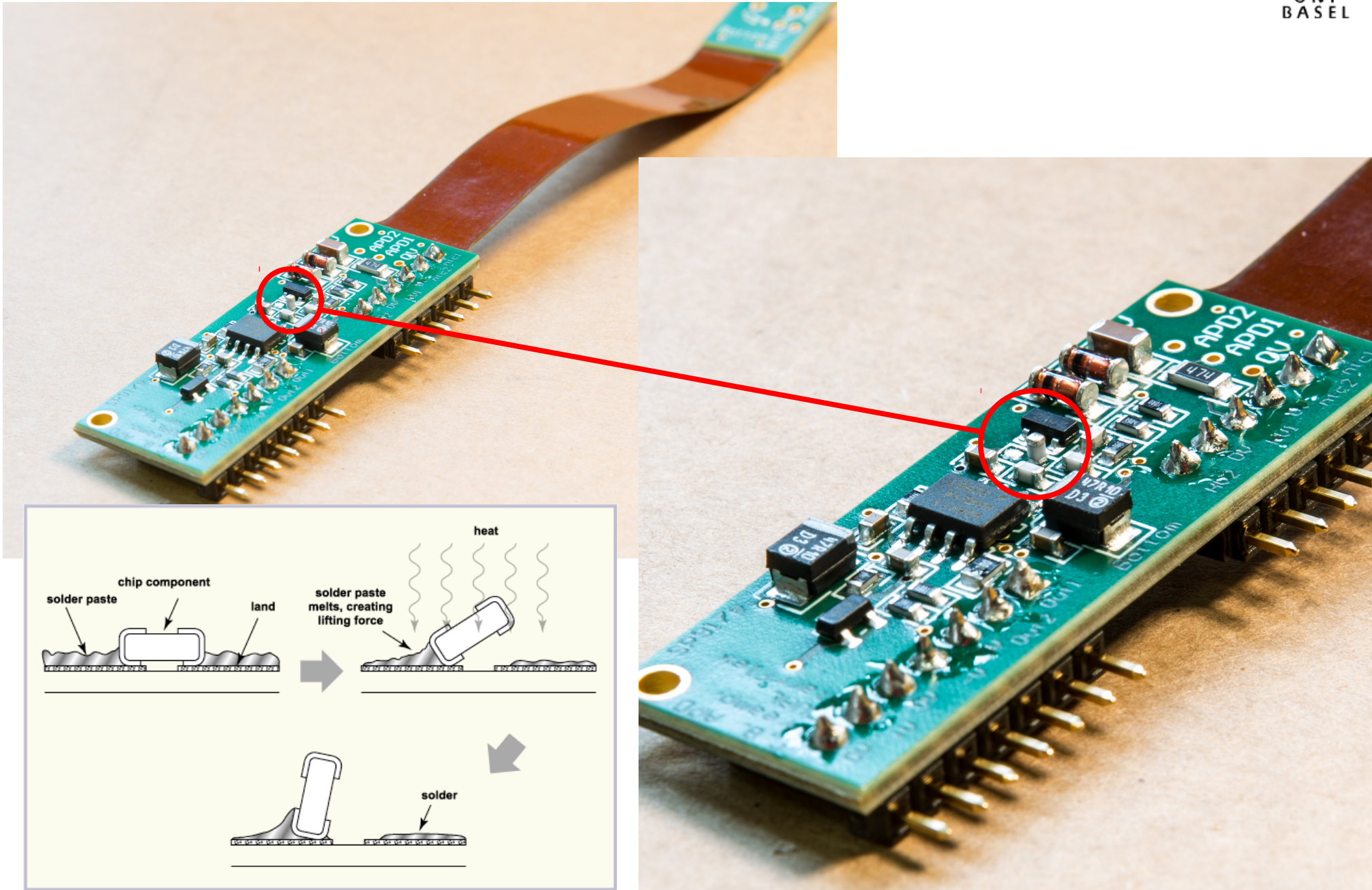
Screenshot



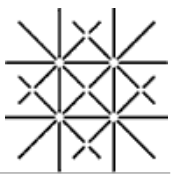
UNI
BASEL



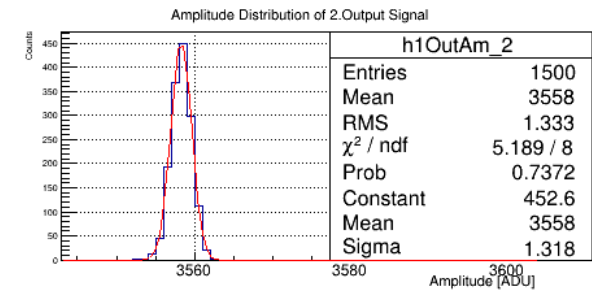
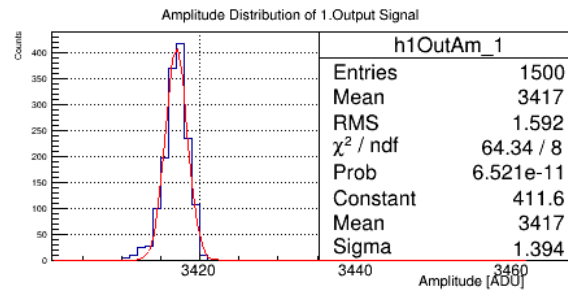
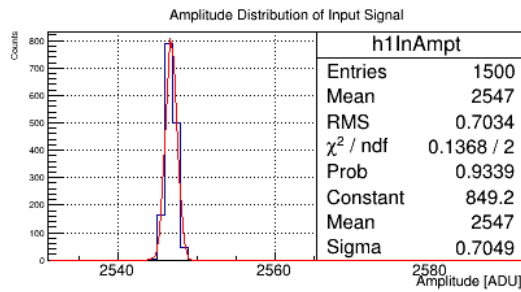
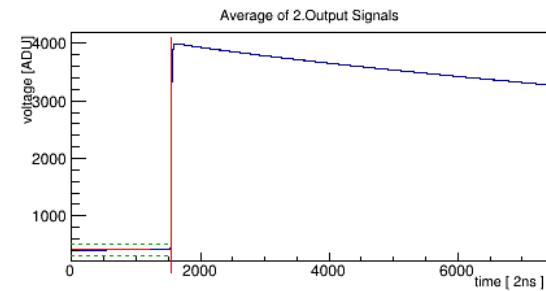
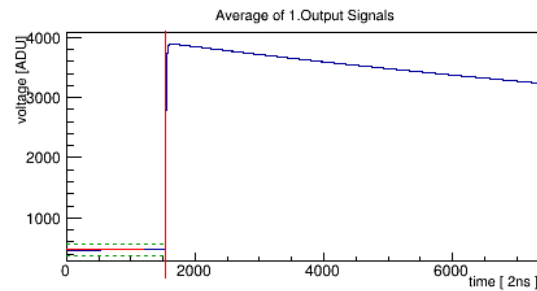
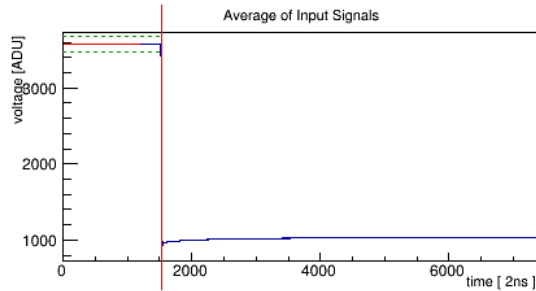
Tombstone SMD effect



Typical Signals



UNI
BASEL



RESULTS OF LNP 0057 A-Nr. 08

In the legends below the RMS, the data corresponds to the fit.

INPUT - SIGNAL

Amplitude: Mean = 2546.776667 [ADU]
Amplitude: RMS = 0.703412

Histogram Data

Mean = 2546.776667 [ADU]
RMS = 0.703412

Fit Data

Mean = 2546.777900 [ADU]
Sigma = 0.704854

1. OUTPUT - SIGNAL

Propagation Delay from Average: 28 ns

Amplitude: Mean = 3416.900000 [ADU]
Amplitude: RMS* = 1.591645
Amplitude: RMS** = 0.888233
Rise Time: Mean = 197.849333 [ns]
Rise Time: RMS = 20.052497
Decay Time: Mean = 62.205880 [us]
Decay Time: RMS = 0.064146

Histogram Data

Mean = 3416.900000 [ADU]
RMS* = 1.591645
RMS** = 0.888233
Mean = 197.849333 [ns]
RMS = 20.052497
Mean = 62.205880 [us]
RMS = 0.064146

Fit Data

Mean = 3416.996117 [ADU]
Sigma* = 1.393730
Sigma** = 0.888877
Mean = 194.044656 [ns]
Sigma = 14.229541
Mean = 62.205287 [us]
Sigma = 0.063532

2. OUTPUT - SIGNAL

Propagation Delay from Average: 28 ns

Amplitude: Mean = 3558.266667 [ADU]
Amplitude: RMS* = 1.332750
Amplitude: RMS** = 0.629338
Rise Time: Mean = 192.244000 [ns]
Rise Time: RMS = 11.288540
Decay Time: Mean = 59.598887 [us]
Decay Time: RMS = 0.072694

Histogram Data

Mean = 3558.266667 [ADU]
RMS* = 1.332750
RMS** = 0.629338
Mean = 192.244000 [ns]
RMS = 11.288540
Mean = 59.598887 [us]
RMS = 0.072694

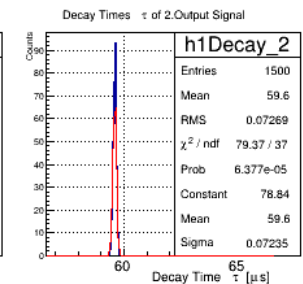
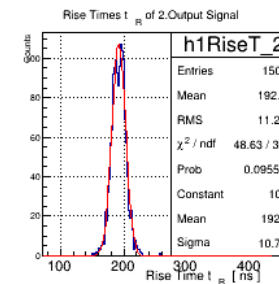
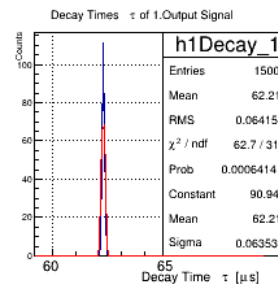
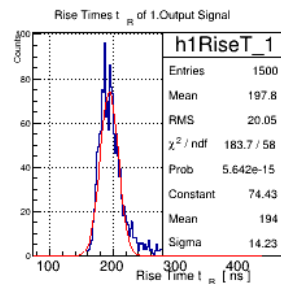
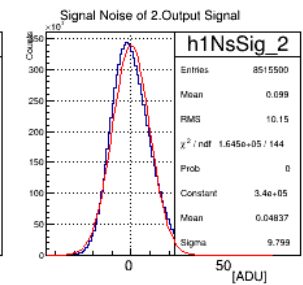
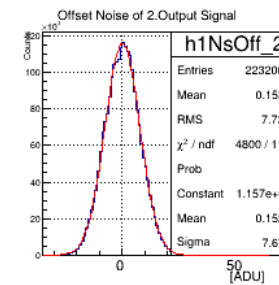
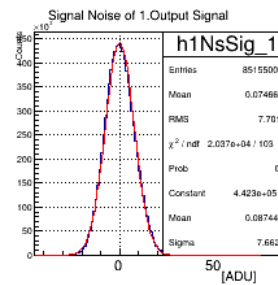
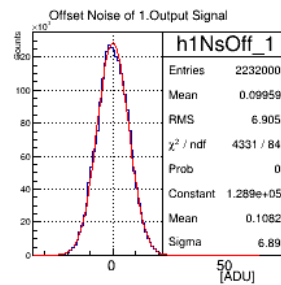
Fit Data

Mean = 3558.275978 [ADU]
Sigma* = 1.317670
Sigma** = 0.612817
Mean = 192.086054 [ns]
Sigma = 10.725472
Mean = 59.597153 [us]
Sigma = 0.072352

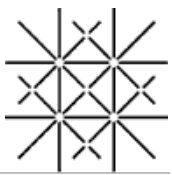
* direct sigma, without manipulation (i.e. includes the sigma of the input)

** manipulated sigma (i.e. excluding input sigma), calculated as follow:

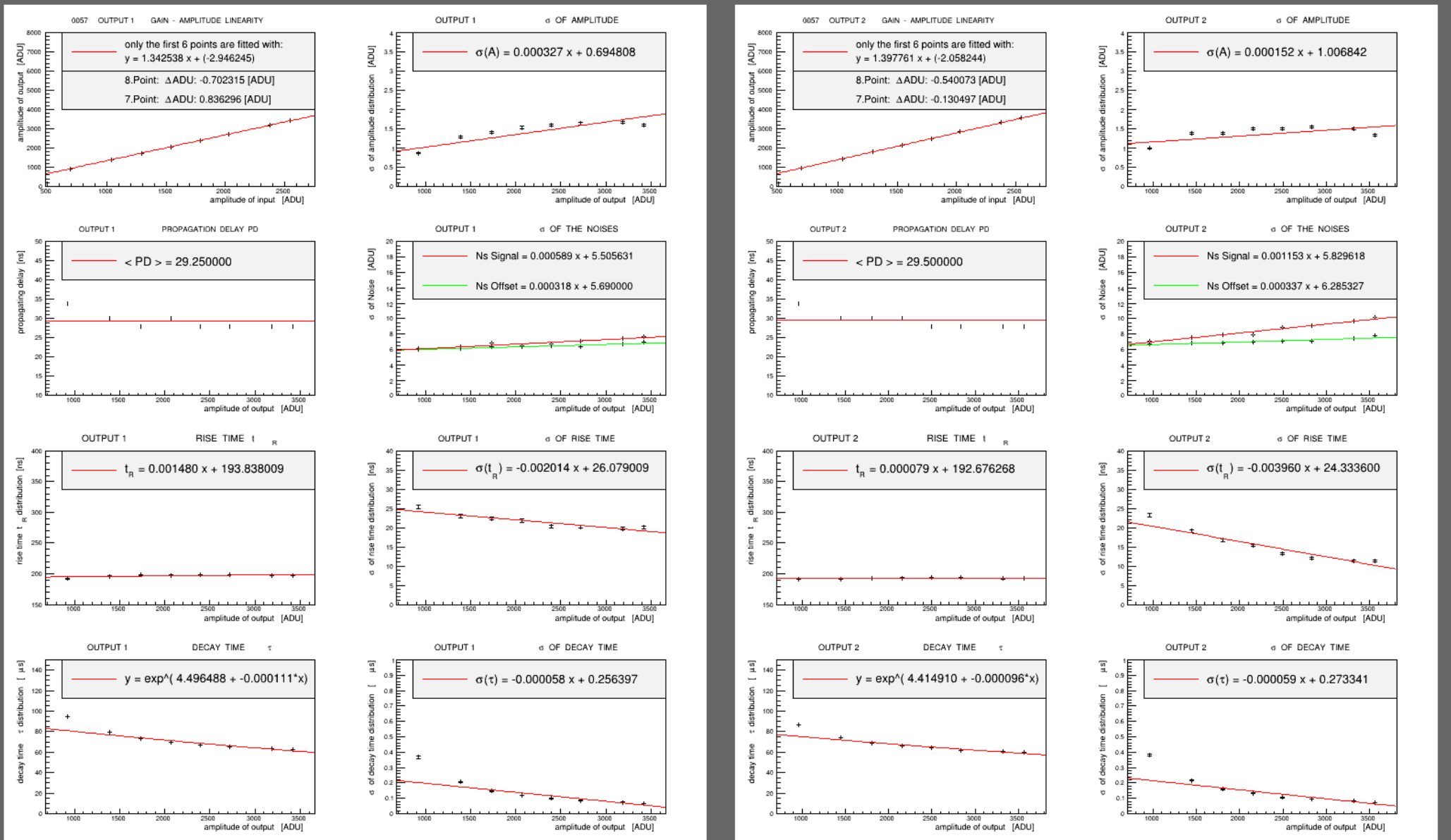
$$\sigma^{**} = \sigma_{out} - \sigma_{in}$$



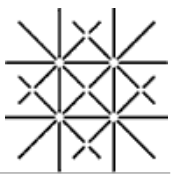
Final Distributions



UNI
BASEL



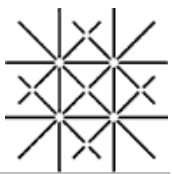
Temperature stability



UNI
BASEL

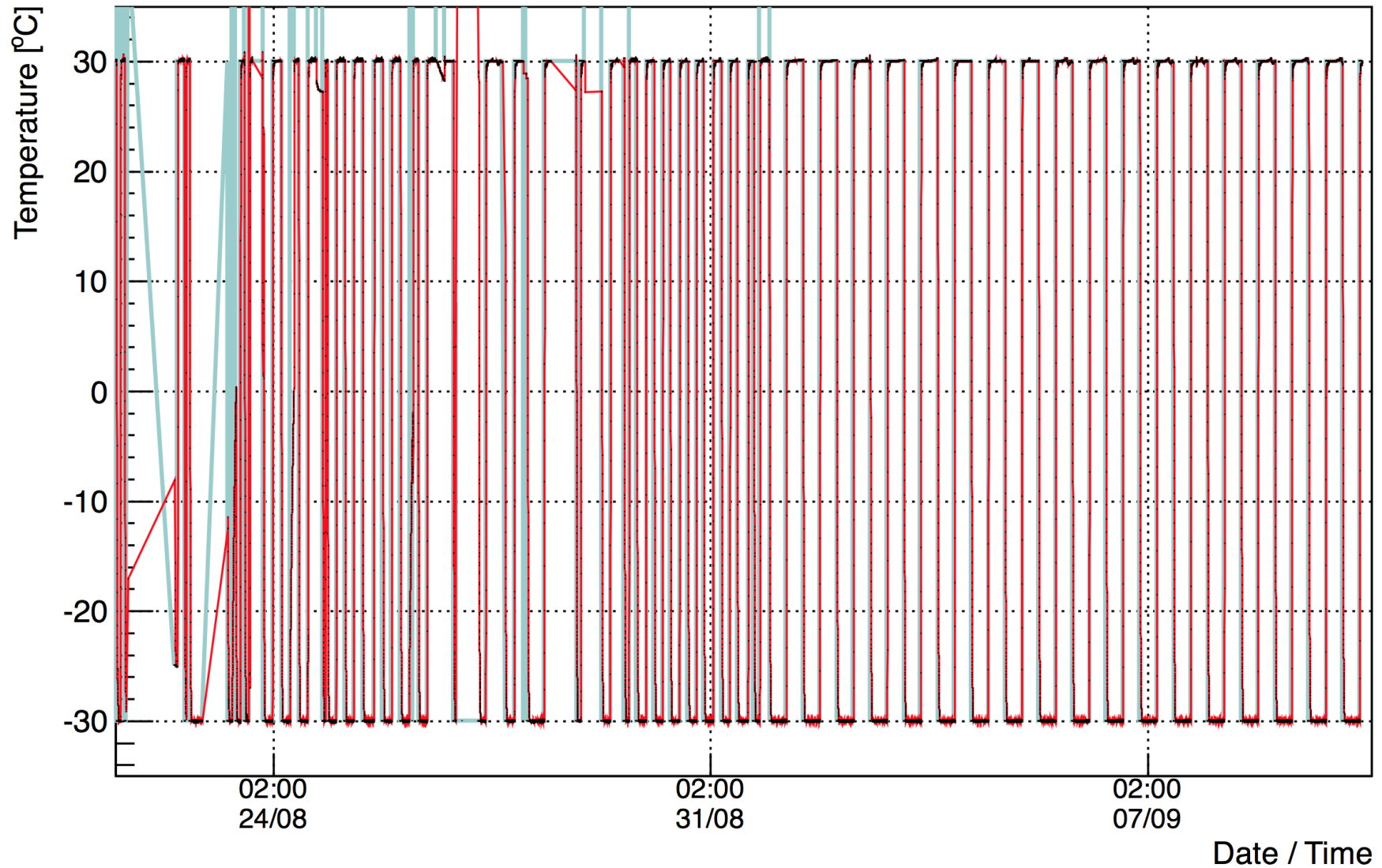


Temperature Cycles

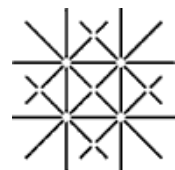


UNI
BASEL

Last update: 09/10/13 12:34:23 | Total N cycles: 42

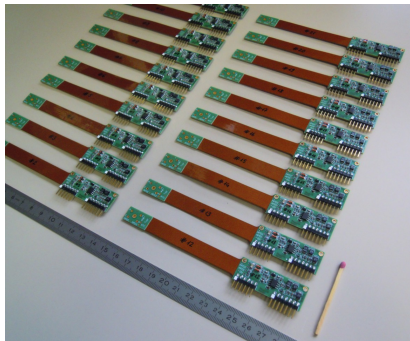


PANDA PreAmp Test Procedure



UNI
BASEL

50 x PreAmp



Extensive test



Up-Down over night

Discrete element Basel-LNP charge 2 voltage preamp

Excellent double burst & amplitude linearity (~1%)

Lab. & beam test are very successful (CERN,MAMI,ELSA)

Some other experiments are interested

NIM paper is in preparation